



Peak Excursion

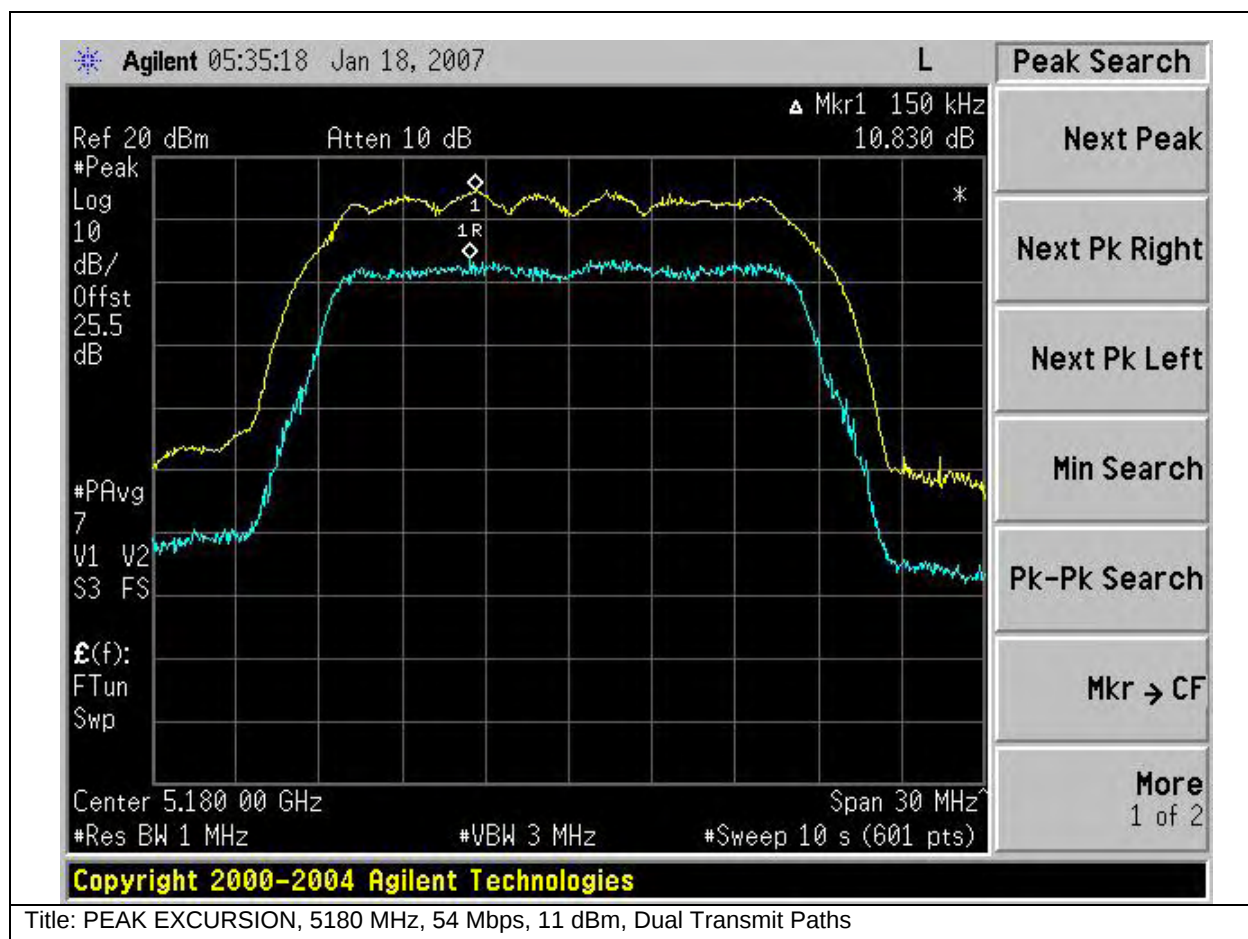
15.407: The ratio of the peak excursion of the modulation envelope (measured using a peak hold function) to the maximum conducted output power (measured as specified above) shall not exceed 13 dB across any 1 MHz bandwidth or the emission bandwidth whichever is less.

Test Number: 25267 Spec ID: 649				
Basic Standard	Applied to	Class	Freq Range	Test Details / Comments
CFR47 Part 15.407(a)6	RF Ports	N/A	5150MHz - 5725MHz	Peak Excursion also complies with LP0002, RSS 210
Operating Mode	Mode : 1, Continuous Transmitting			
Power Input	110, 60Hz (+/-20%)			
Overall Result	Pass			
Comments	No further comments			
Deviation	There were no deviations from the specification			

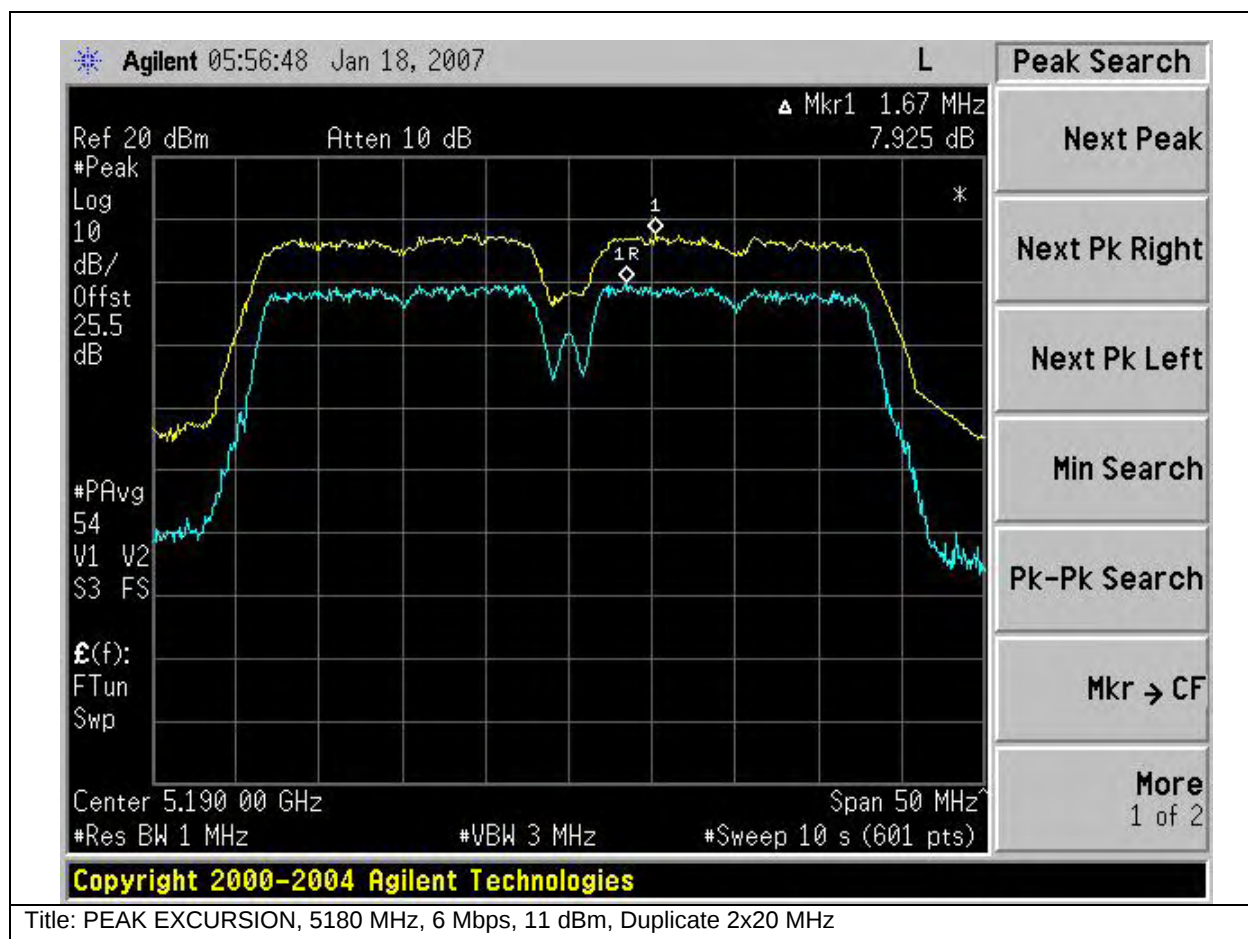
System Number	Description	Samples	System under test	Support equipment
1	EUT	S01, S02, S03 and S04	☒	☐

Frequency (MHz)	Mode	Data Rate (Mbps)	Peak Excursion (dB)	Limit (dB)	Margin (dB)
5180	Dual	54	10.8	13	2.2
5180	Duplicate	6	7.9	13	5.1
5260	Dual	54	10.7	13	2.3
5260	Duplicate	6	7.5	13	5.5
5320	Dual	54	11.2	13	1.8
5320	Duplicate	6	7.2	13	5.8
5500	Dual	54	10.8	13	2.2
5500	Duplicate	6	7.9	13	5.1
5600	Dual	54	9.7	13	3.3
5600	Duplicate	6	8.2	13	4.8
5680	Duplicate	6	7.2	13	5.8
5700	Dual	54	9.7	13	3.3

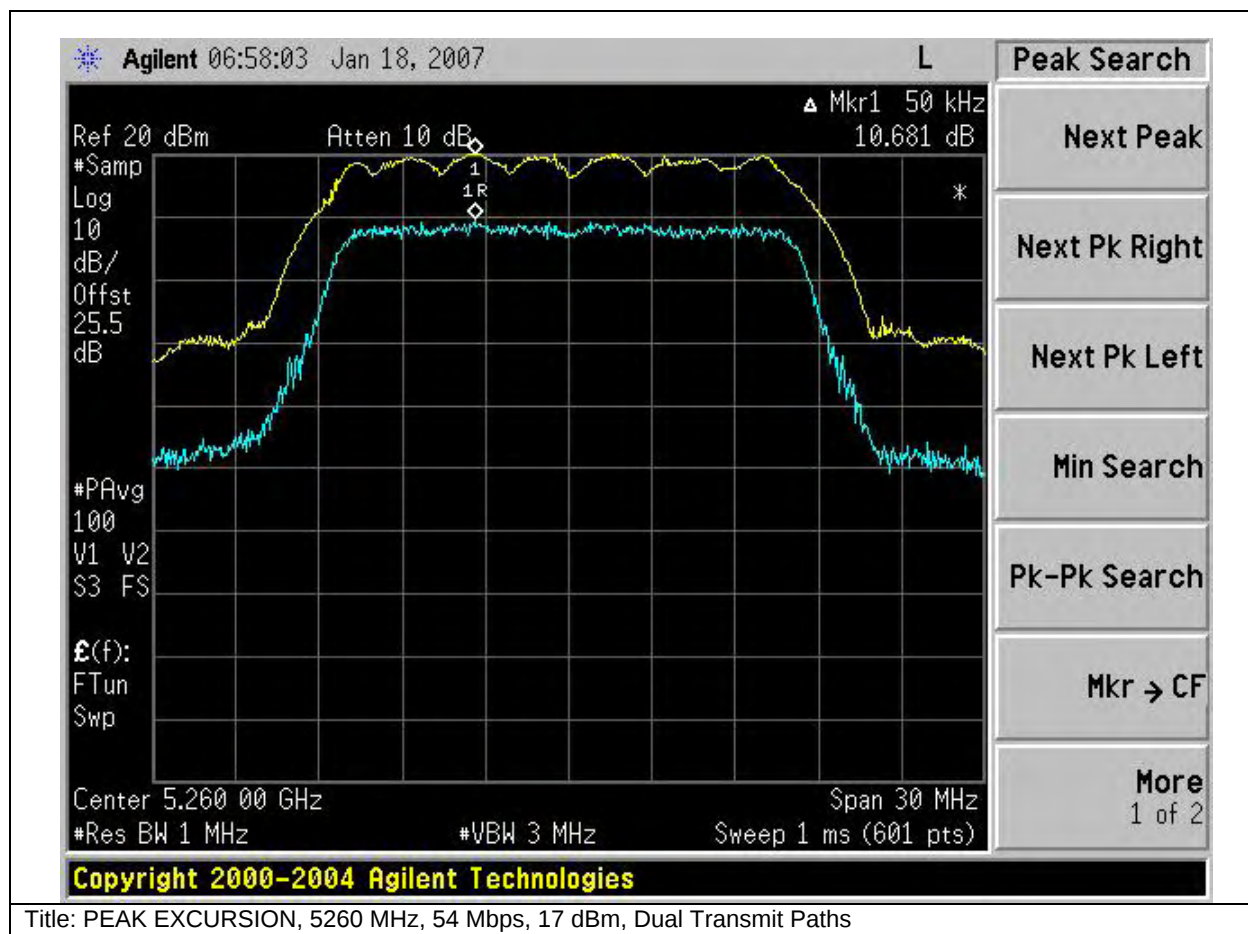
Subtest Number: 25267 - 3		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	DIRECT	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



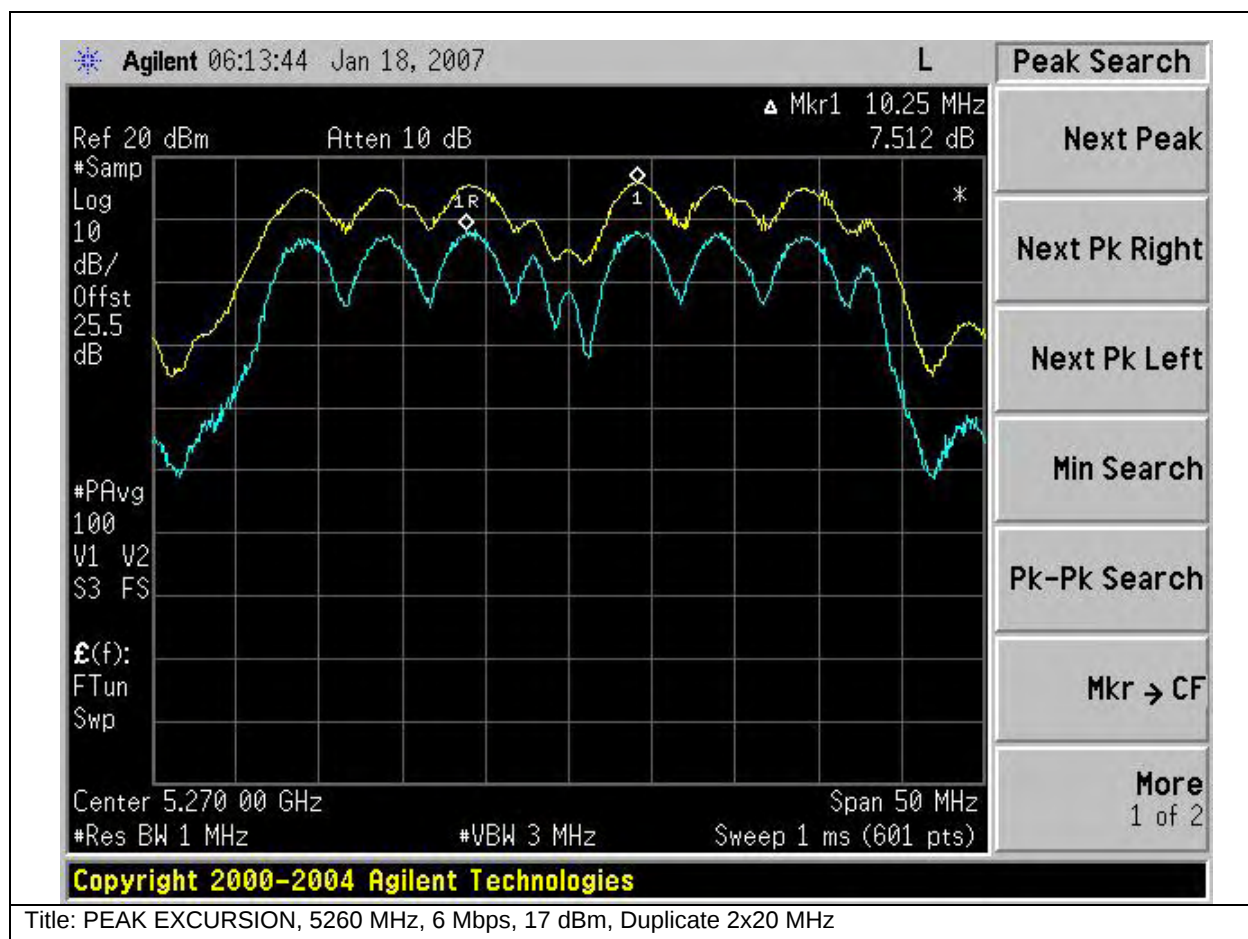
Subtest Number: 25267 - 1		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



Subtest Number: 25267 - 9		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	

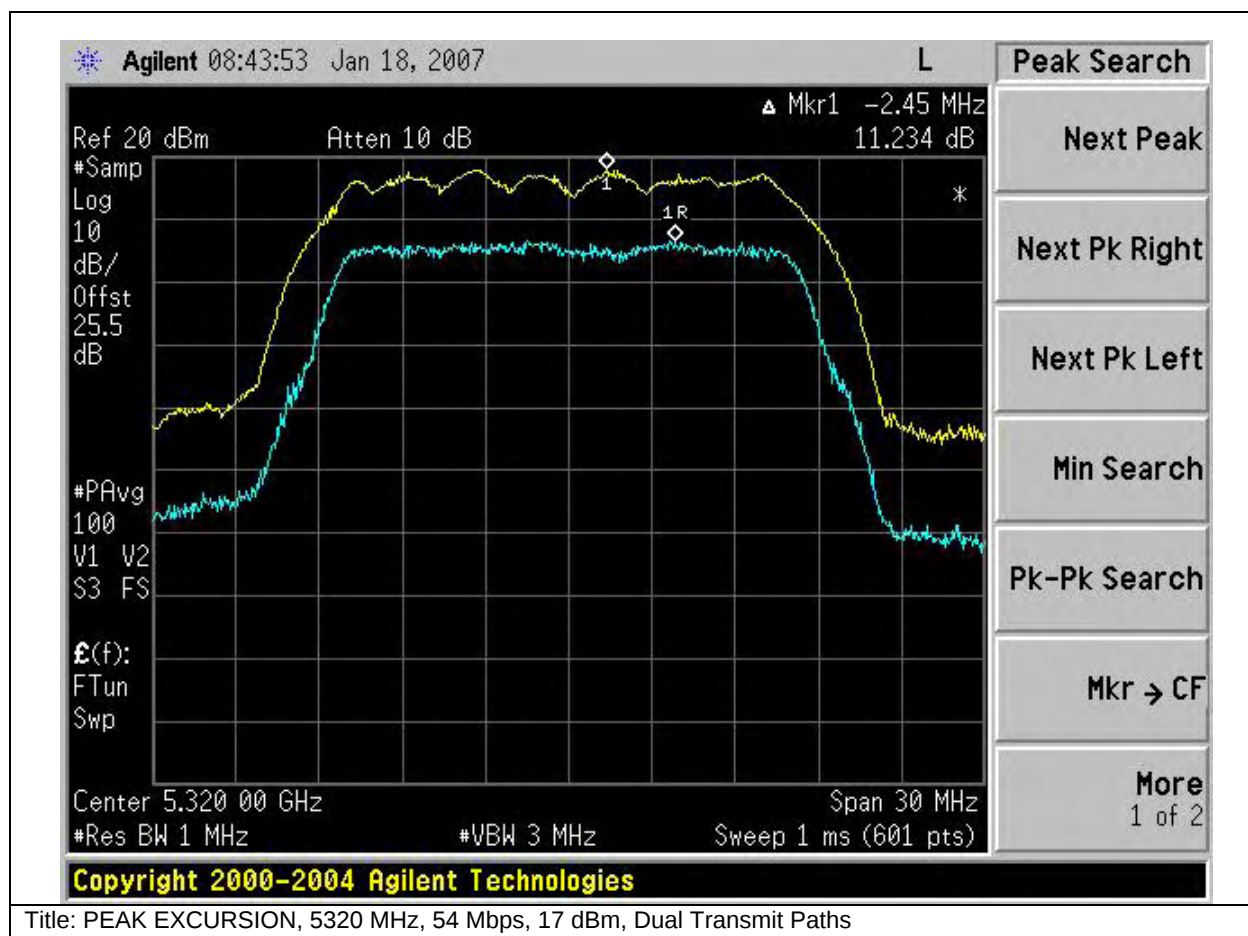


Subtest Number: 25267 - 7		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	

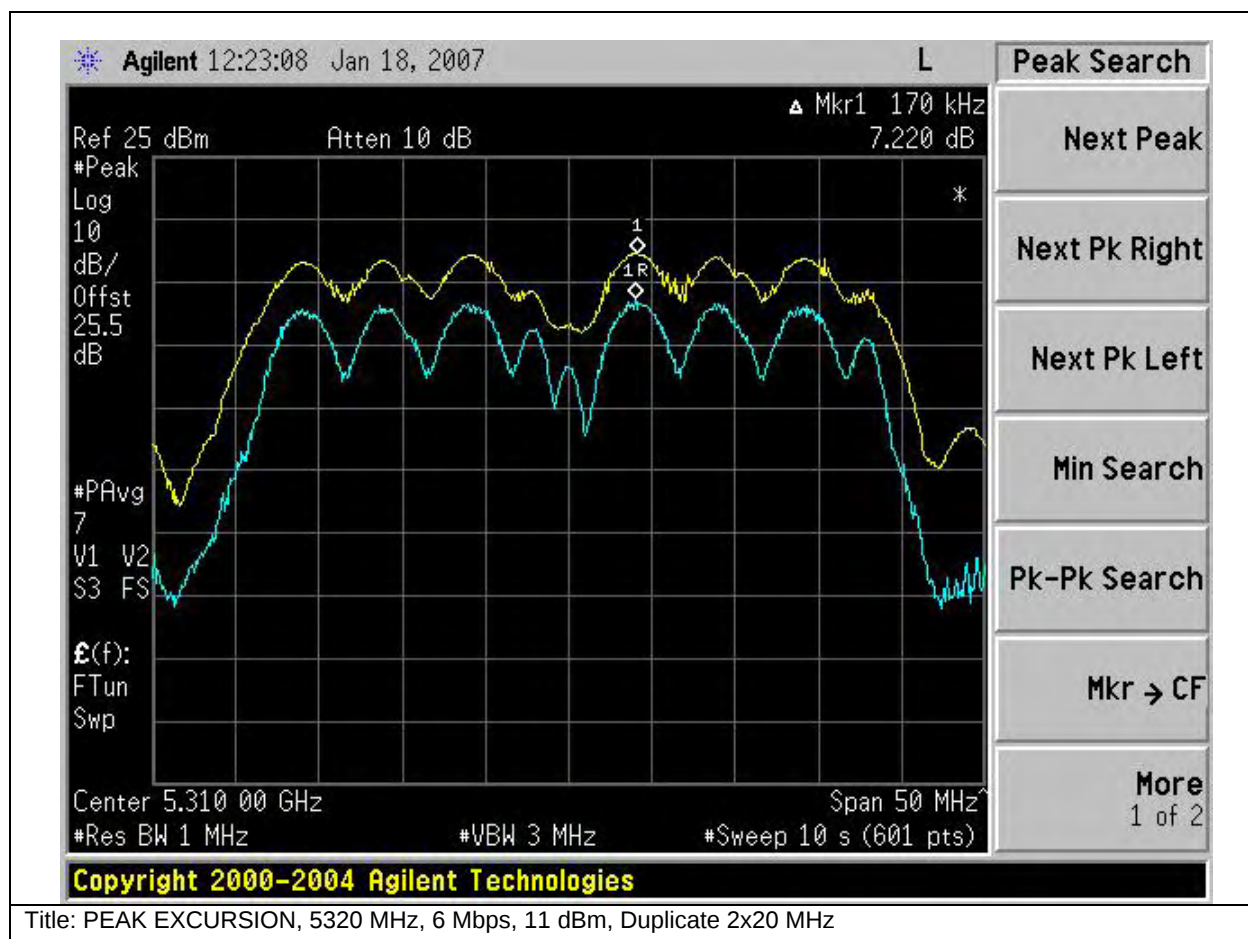




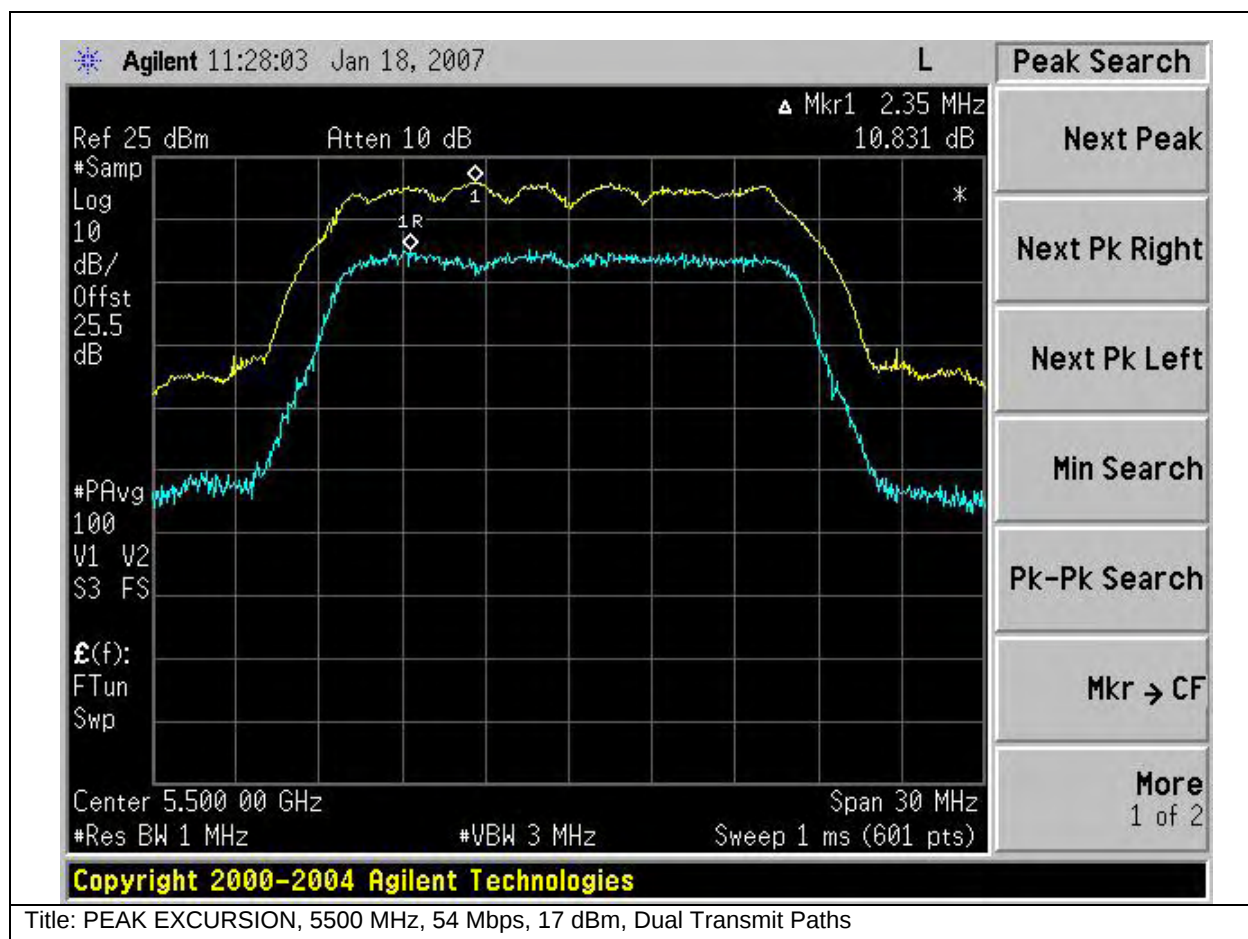
Subtest Number: 25267 - 21		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



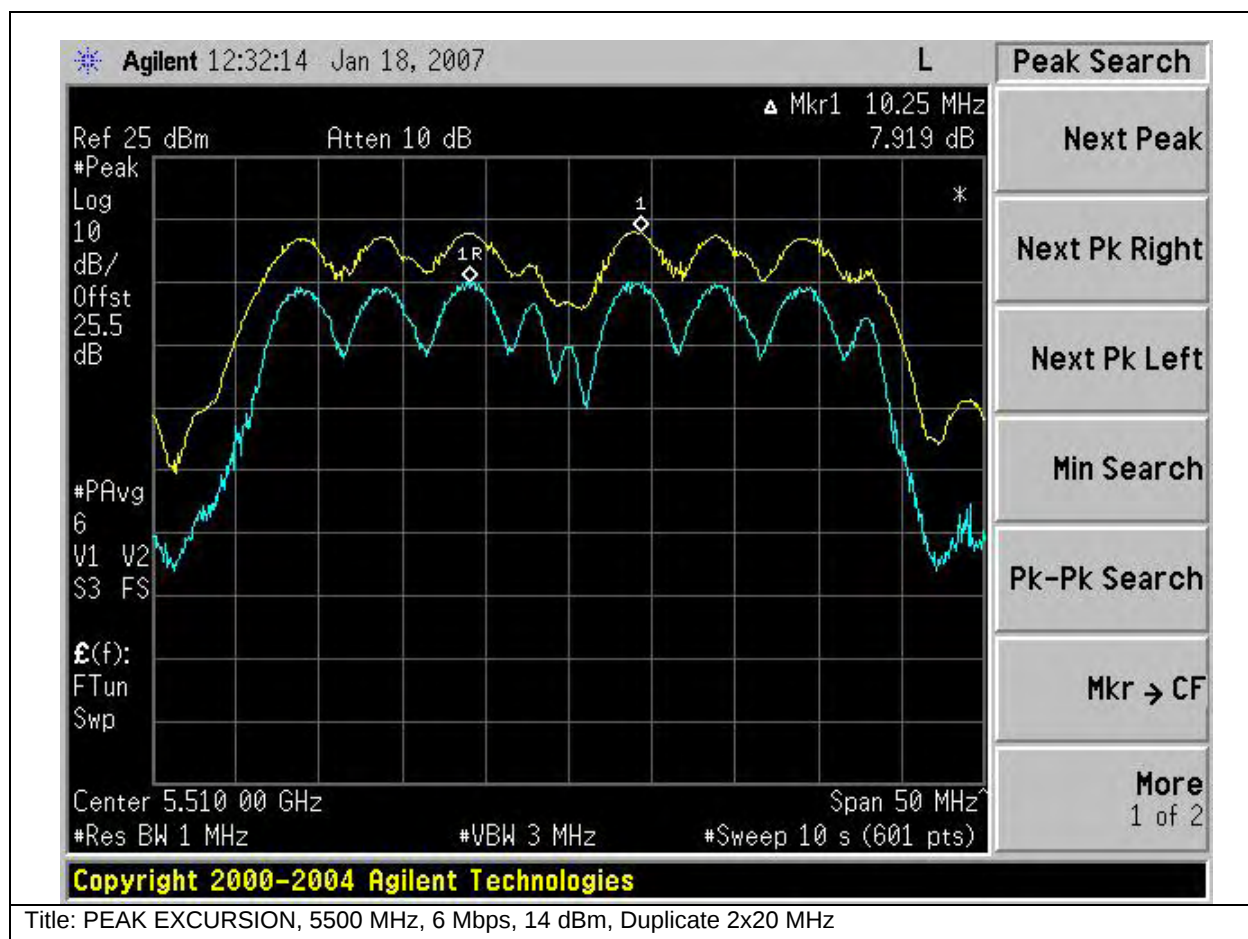
Subtest Number: 25267 - 19		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



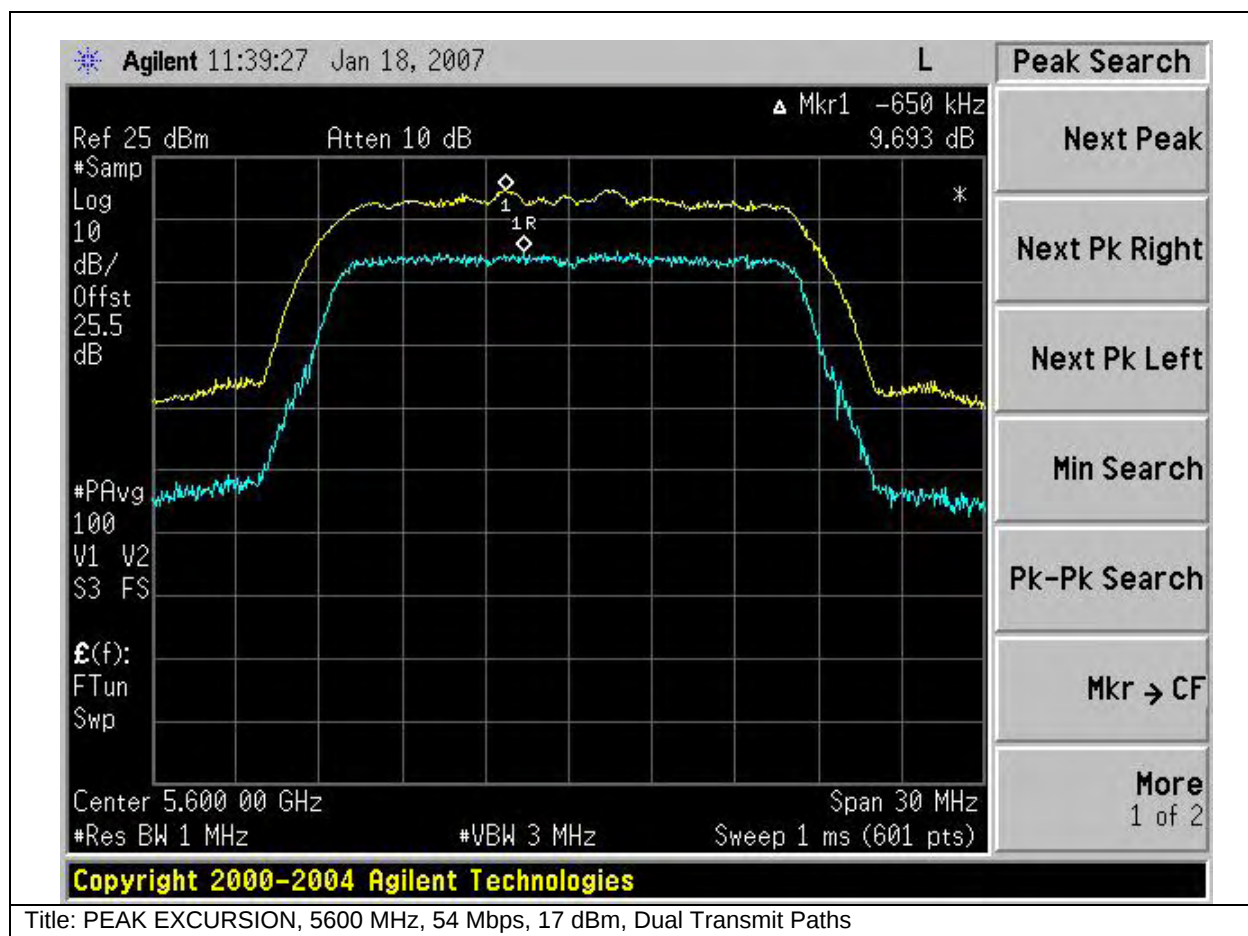
Subtest Number: 25267 - 27		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



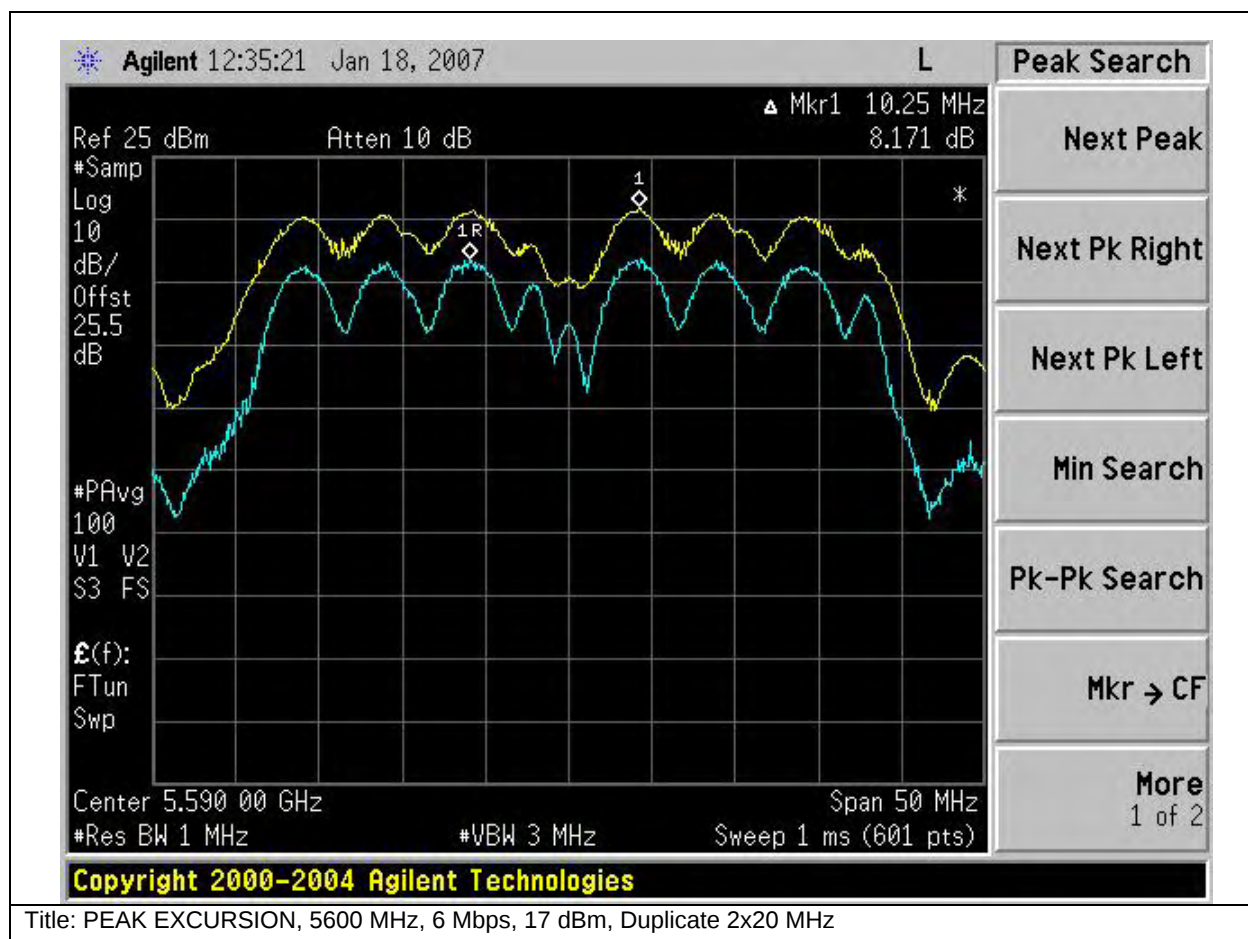
Subtest Number: 25267 - 25		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



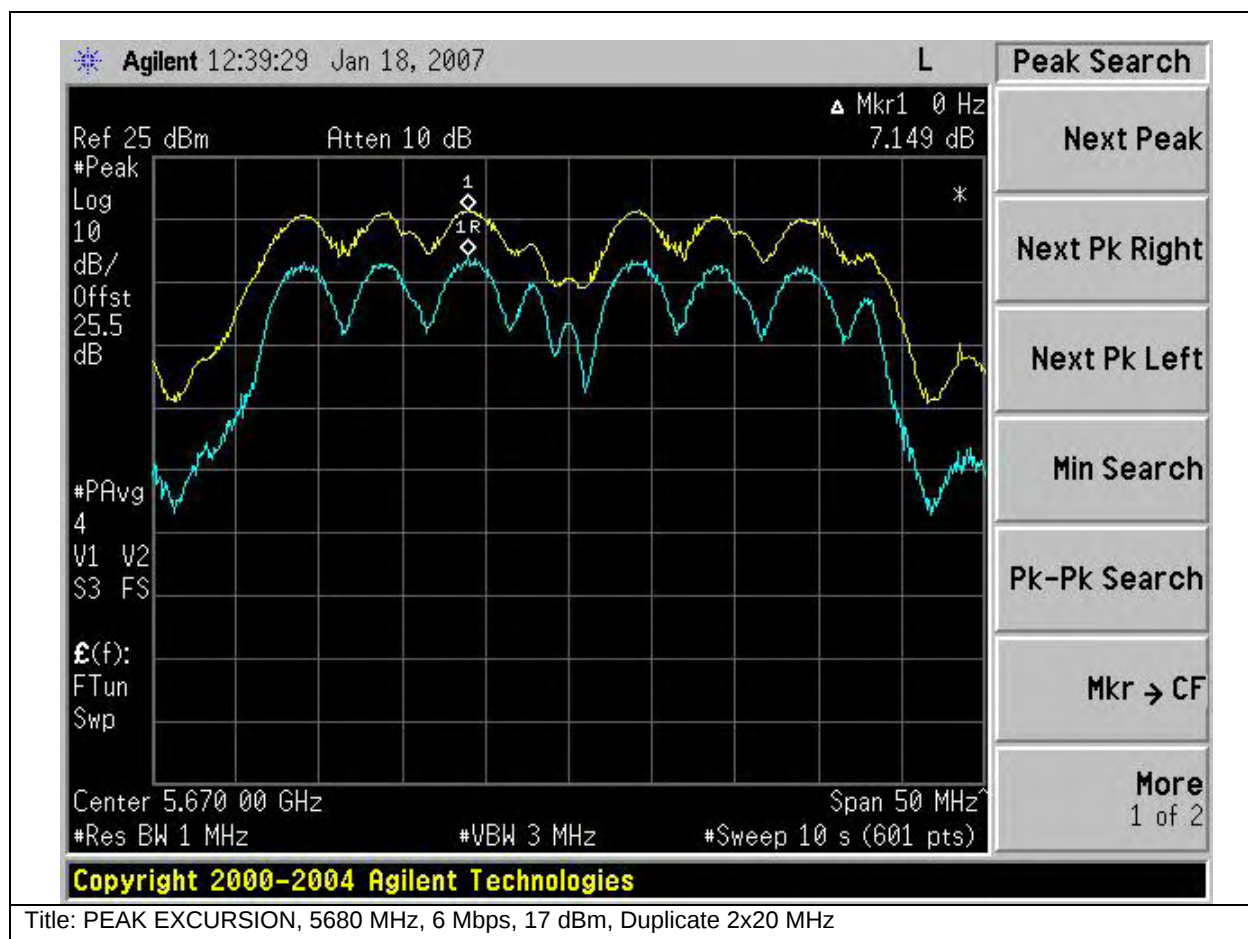
Subtest Number: 25267 - 33		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



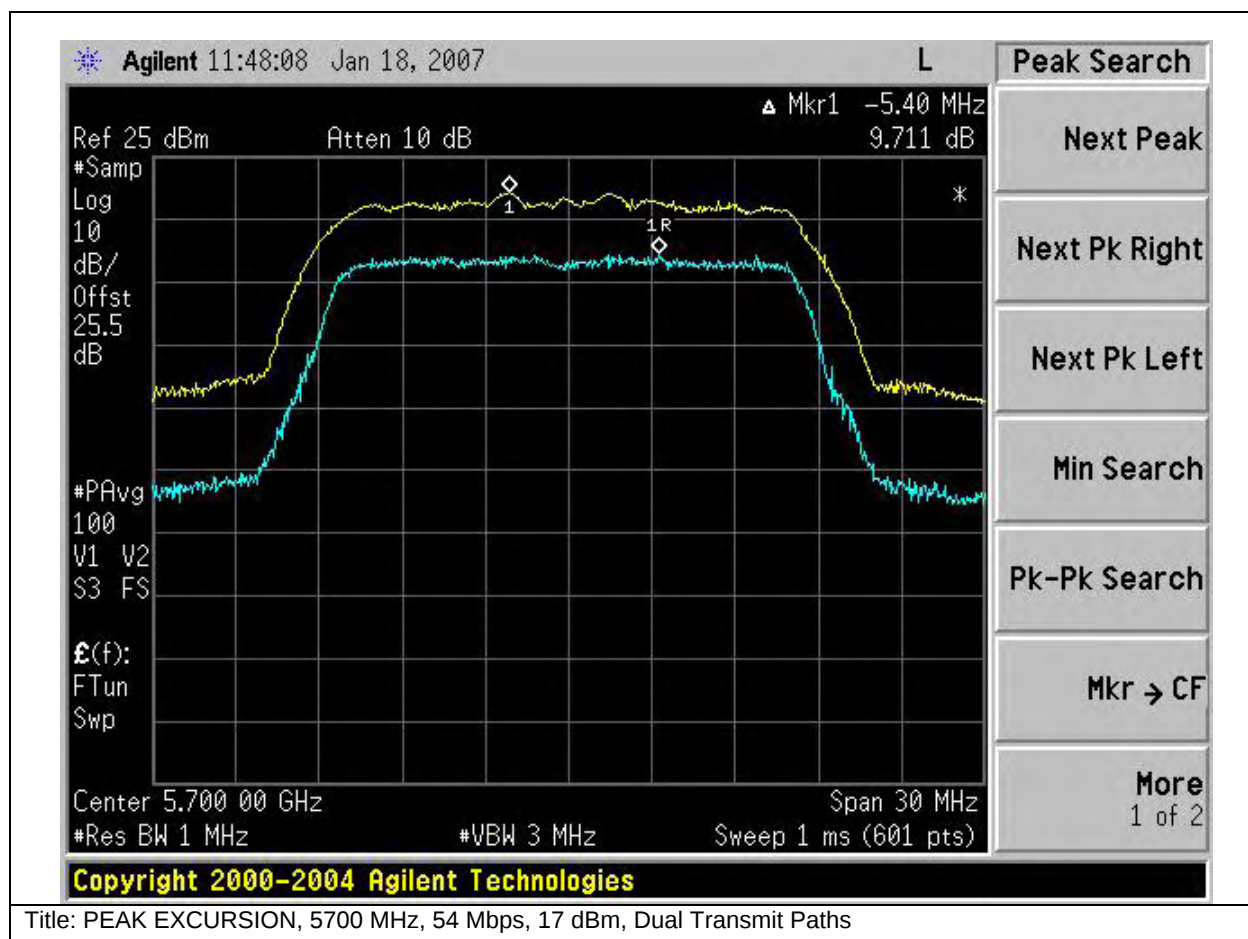
Subtest Number: 25267 - 31		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



Subtest Number: 25267 - 37		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



Subtest Number: 25267 - 40		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	





Conducted Spurious Emissions

15.407: For transmitters operating in the 5.15-5.25 GHz band: all emissions outside of the 5.15-5.35 GHz band shall not exceed an EIRP of -27dBm/MHz.

For transmitters operating in the 5.25-5.35 GHz band: all emissions outside of the 5.15-5.35 GHz band shall not exceed an EIRP of -27dBm/MHz. Devices operating in the 5.25-5.35 GHz band that generate emissions in the 5.15-5.25 GHz band must meet all applicable technical requirements for operation in the 5.15-5.25 GHz band (including indoor use) or alternatively meet an out-of-band emission EIRP limit of -27 dBm/MHz in the 5.15-5.25 GHz band.

For transmitters operating in the 5.47-5.725 GHz band: all emissions outside of the 5.47-5.725 GHz band shall not exceed an EIRP of -27dBm/MHz.

15.247: In any 100 kHz bandwidth outside the frequency band in which the digitally modulated intentional radiator is operating, the radio frequency power that is produced by the intentional radiator shall be at least 30 dB below that in the 100 kHz bandwidth within the band that contains the highest level of the desired power.

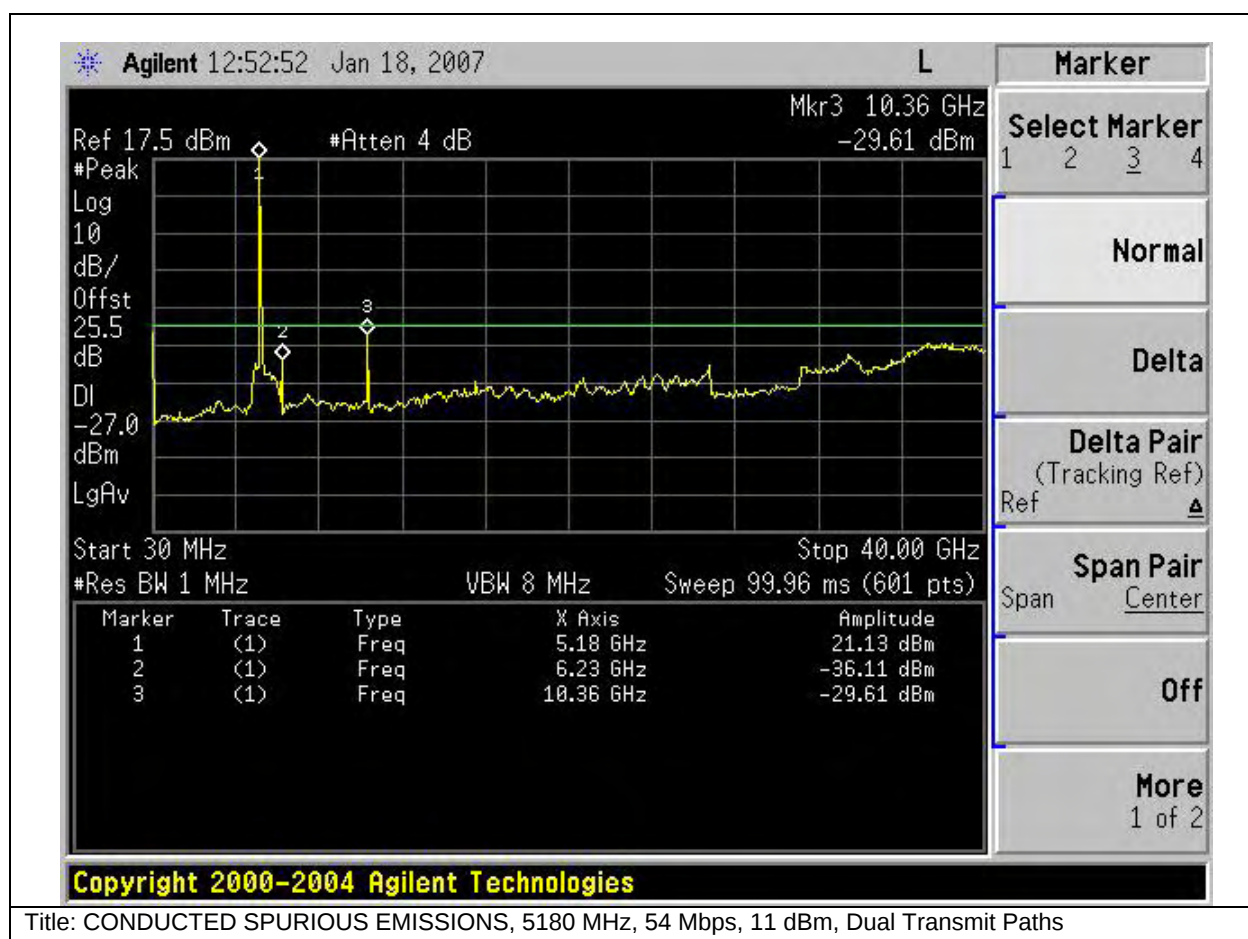
Test Number: 25260 Spec ID: 652				
Basic Standard	Applied to	Class	Freq Range	Test Details / Comments
Conducted Spurious Emissions	RF Ports	N/A	30MHz - xGHz	Also complies with RSS 210, LP0002
Operating Mode	Mode : 1, Continuous Transmitting			
Power Input	110, 60Hz (+/-20%)			
Overall Result	Pass			
Comments	No further comments			
Deviation	There were no deviations from the specification			

System Number	Description	Samples	System under test	Support equipment
1	EUT	S01, S02, S03 and S04	☒	☐

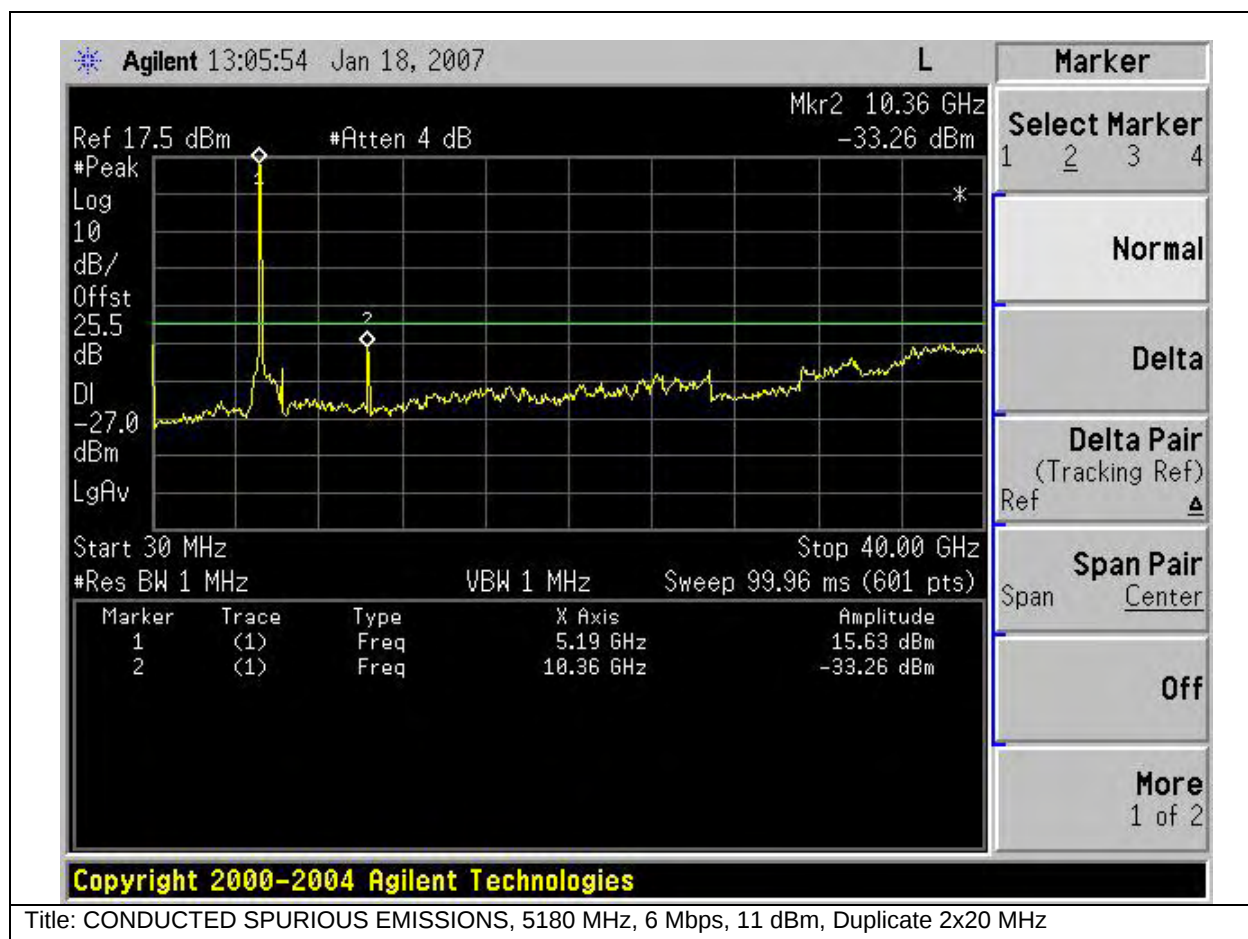


Frequency (MHz)	Mode	Data Rate (Mbps)	Conducted Spurs (dBm)	Limit (dBm)	Margin (dB)
5180	Dual	54	-29.6	-27	2.6
5180	Duplicate	6	-33.3	-27	6.3
5260	Dual	54	-37.0	-27	10
5260	Duplicate	6	-36.9	-27	9.1
5320	Dual	54	-35.9	-27	8.9
5320	Duplicate	6	-37.6	-27	10.6
5500	Dual	54	-34.5	-27	7.5
5500	Duplicate	6	-34.2	-27	7.2
5600	Dual	54	-35.5	-27	8.5
5600	Duplicate	6	-34.5	-27	7.5
5680	Duplicate	6	-34.6	-27	7.6
5700	Dual	54	-32.6	-27	5.6
5745	Dual BF	54	-47.9	-27	20.9
5745	Duplicate	6	-47.7	-27	20.7
5785	Dual BF	54	-49.5	-27	22.5
5785	Duplicate	6	-49.6	-27	22.6
5805	Duplicate	6	-49.6	-27	22.6
5825	Dual BF	54	-48.0	-27	21.0

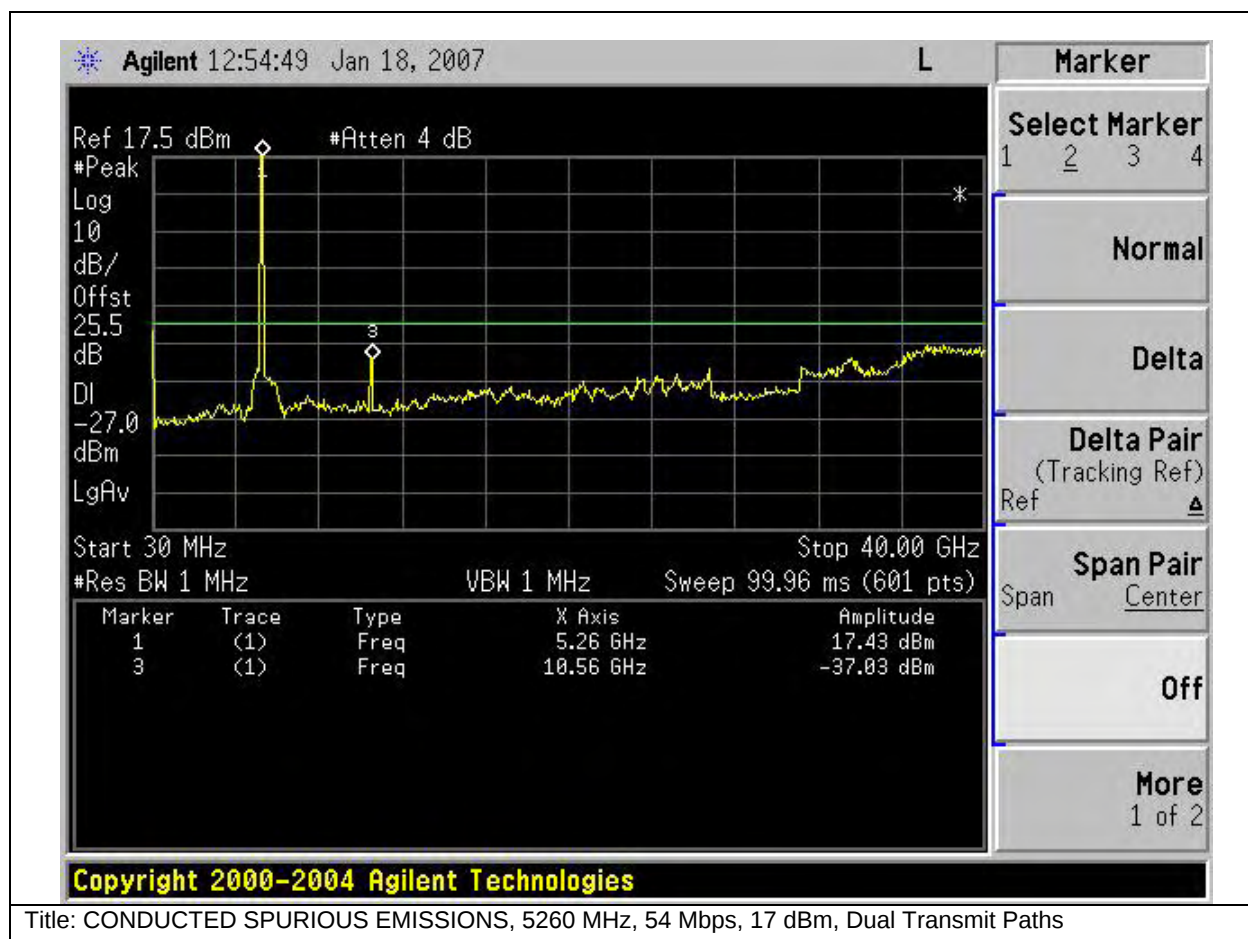
Subtest Number: 25260 - 2		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



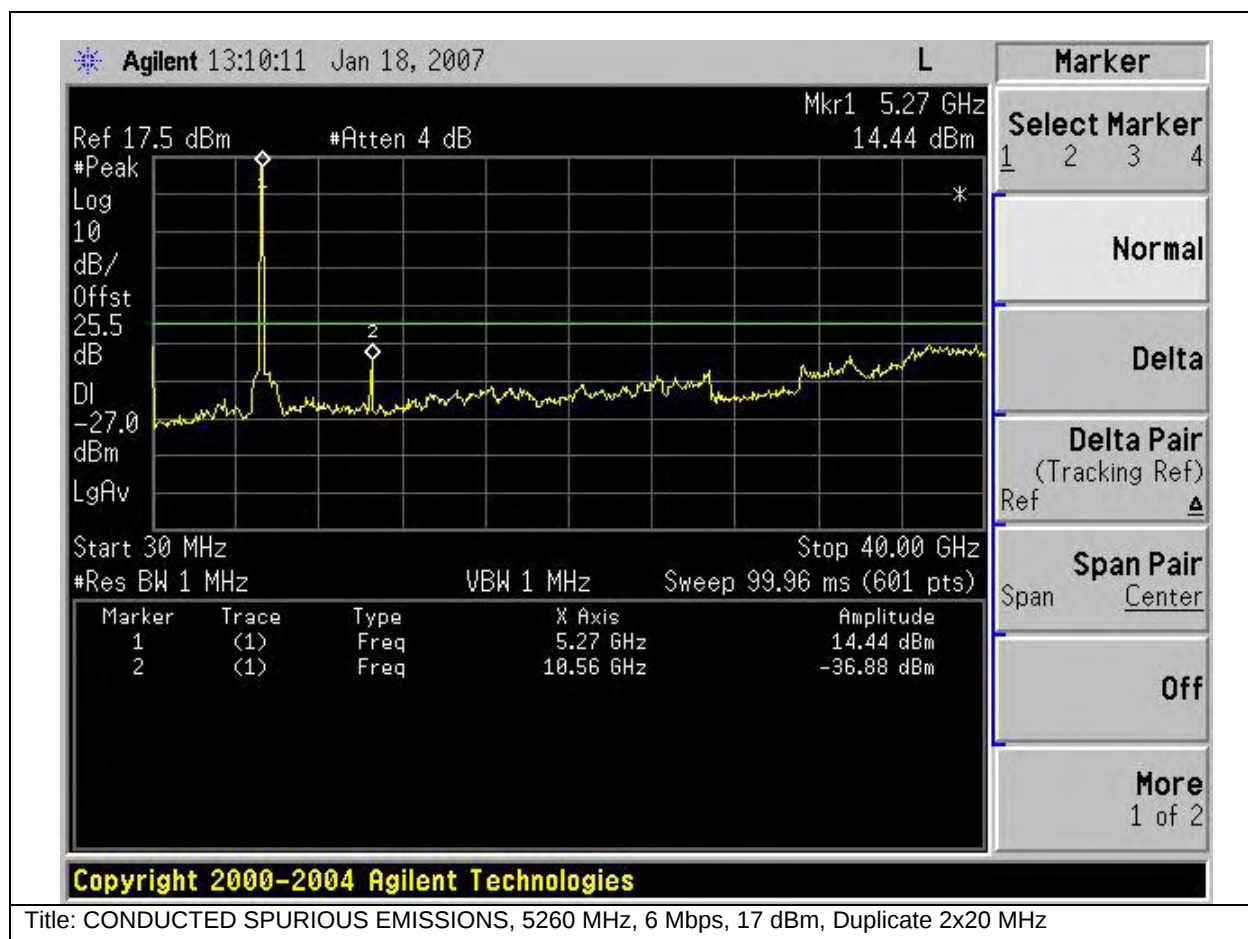
Subtest Number: 25260 - 1		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



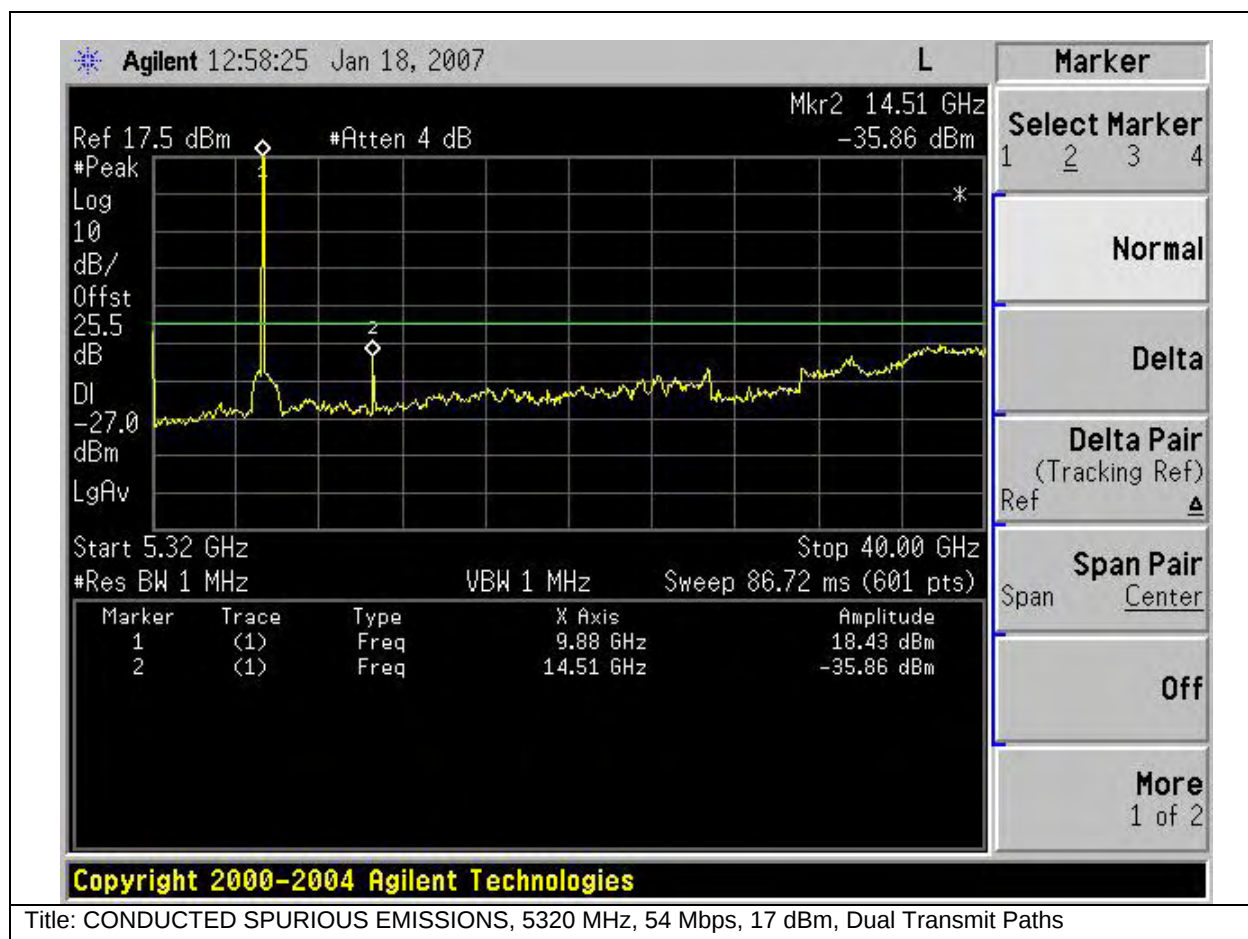
Subtest Number: 25260 - 4		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



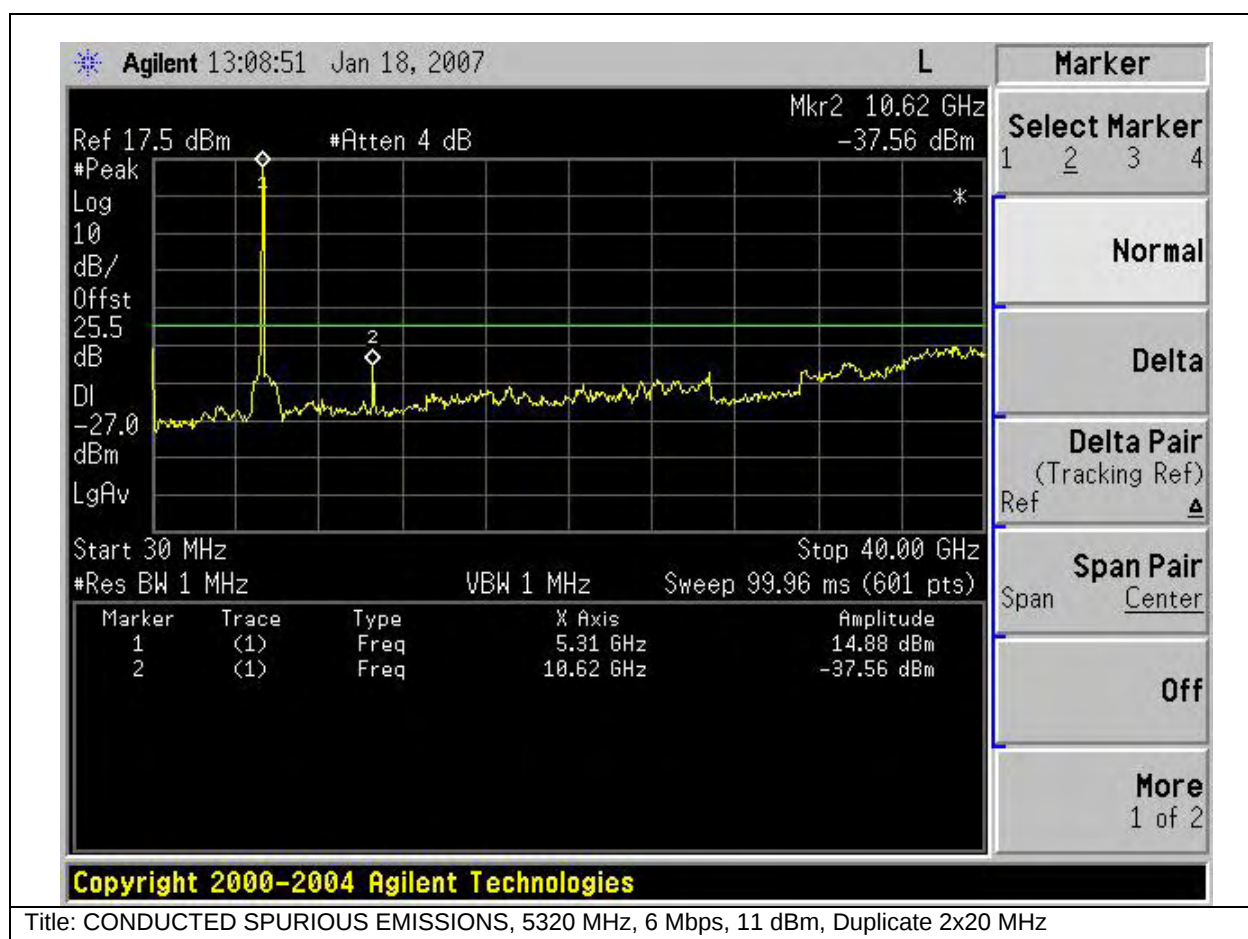
Subtest Number: 25260 - 3		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



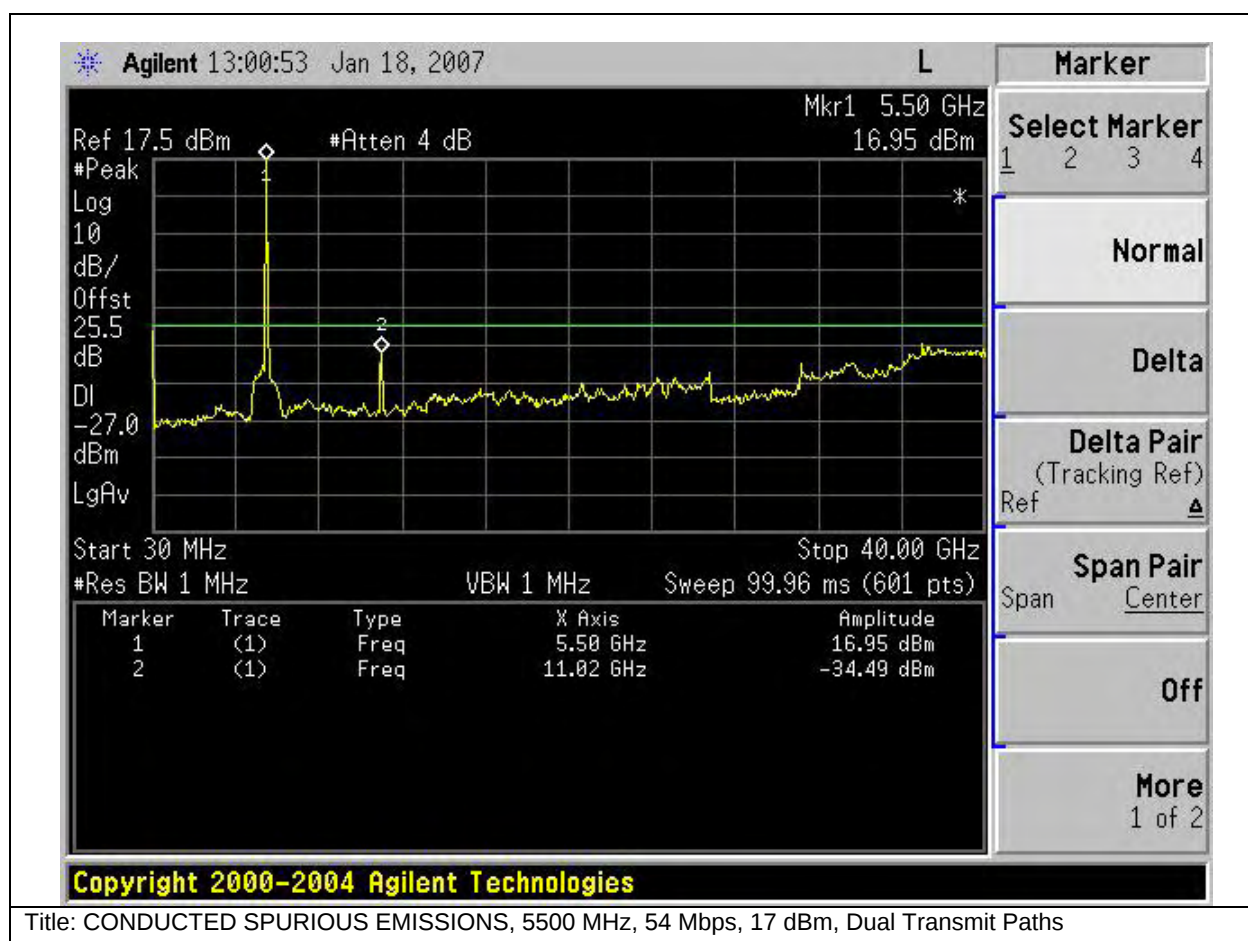
Subtest Number: 25260 - 8		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



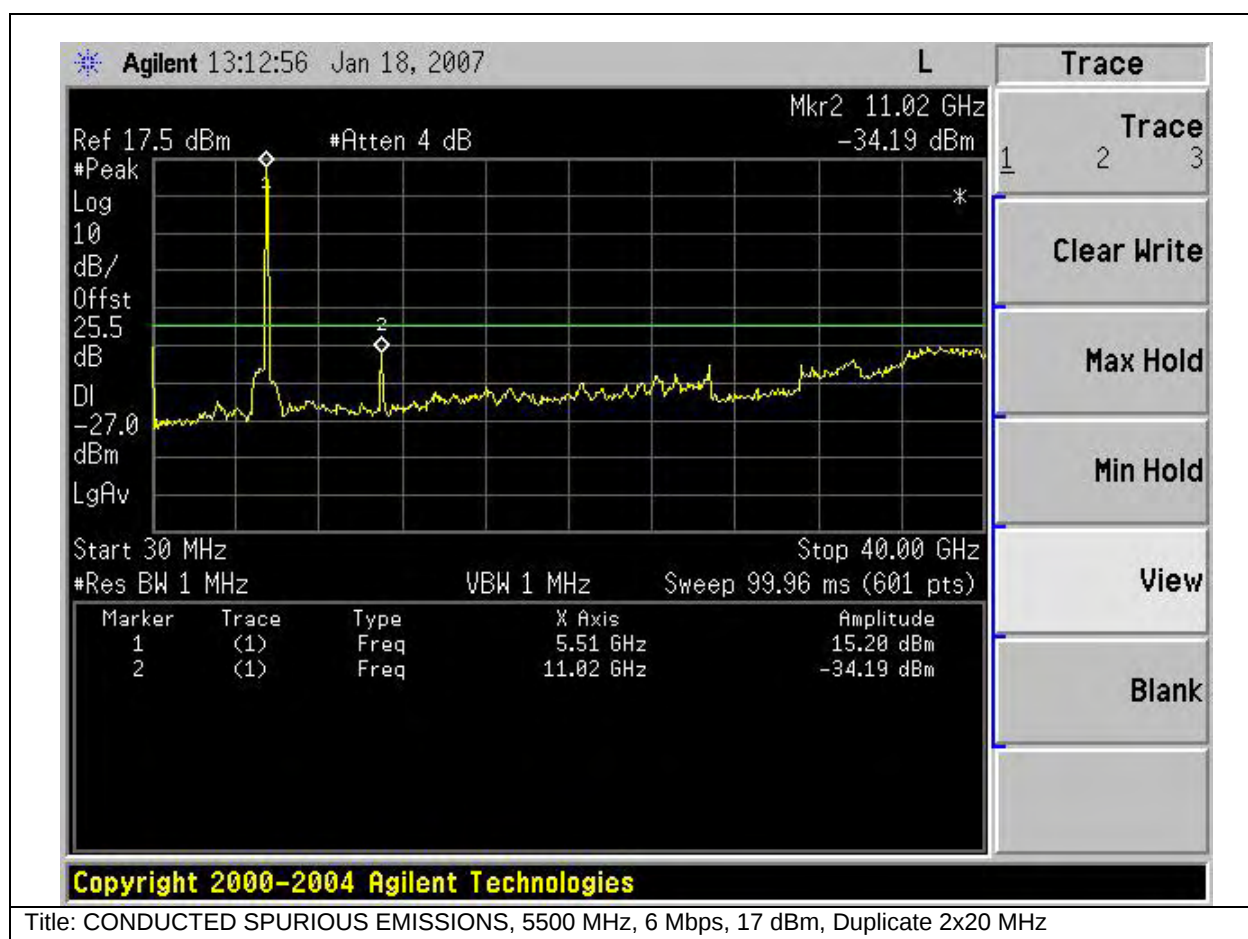
Subtest Number: 25260 - 7		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



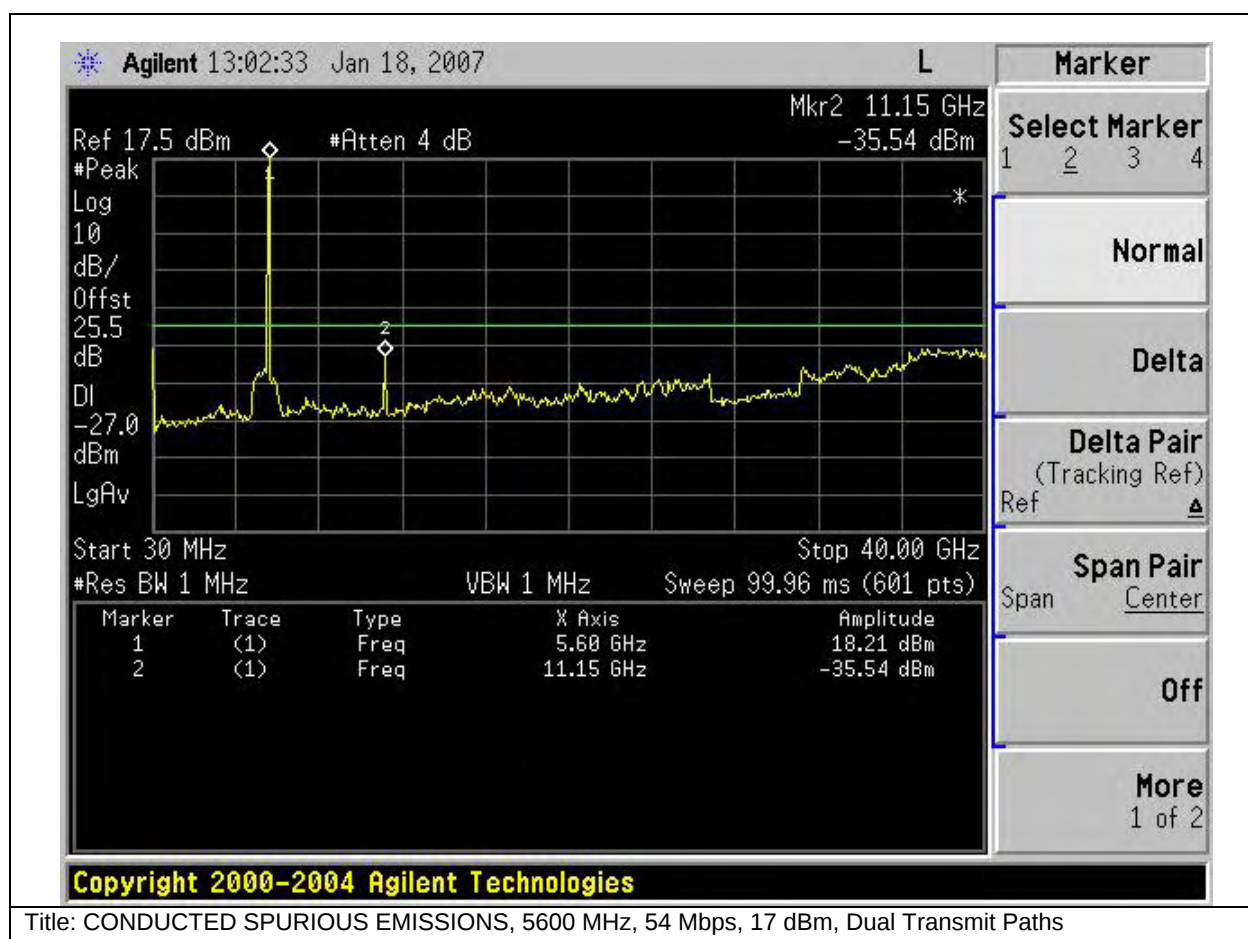
Subtest Number: 25260 - 10		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



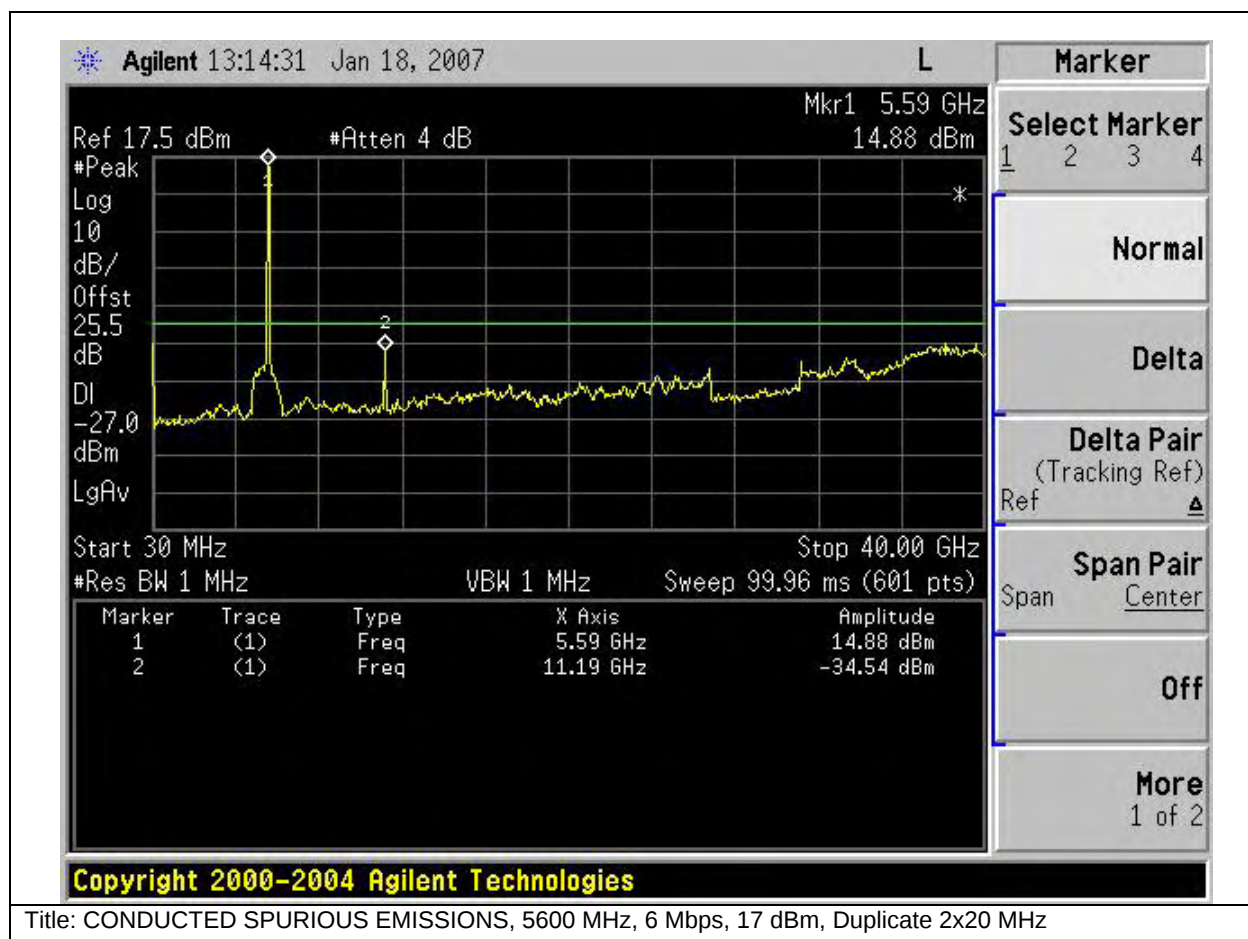
Subtest Number: 25260 - 9		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



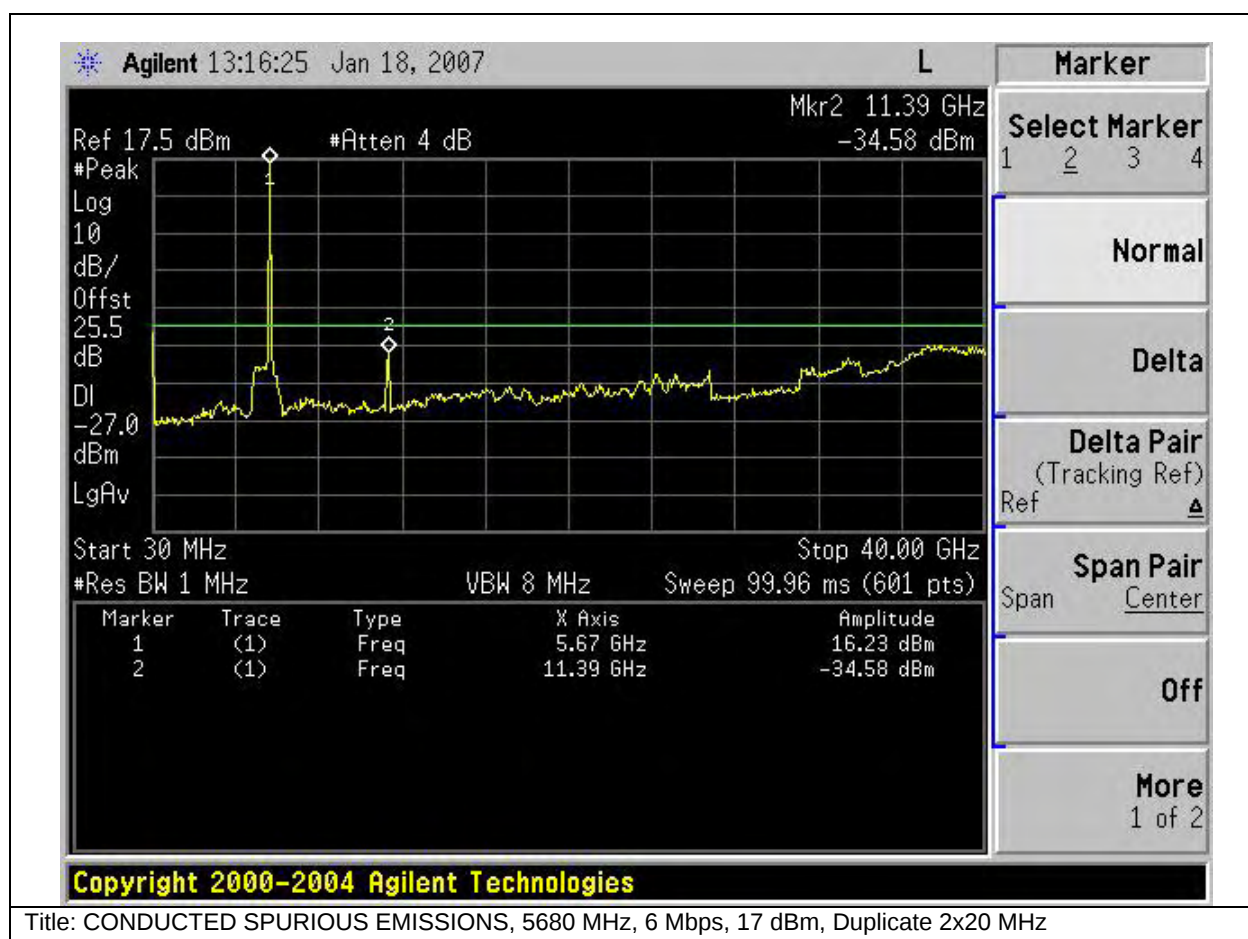
Subtest Number: 25260 - 12		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



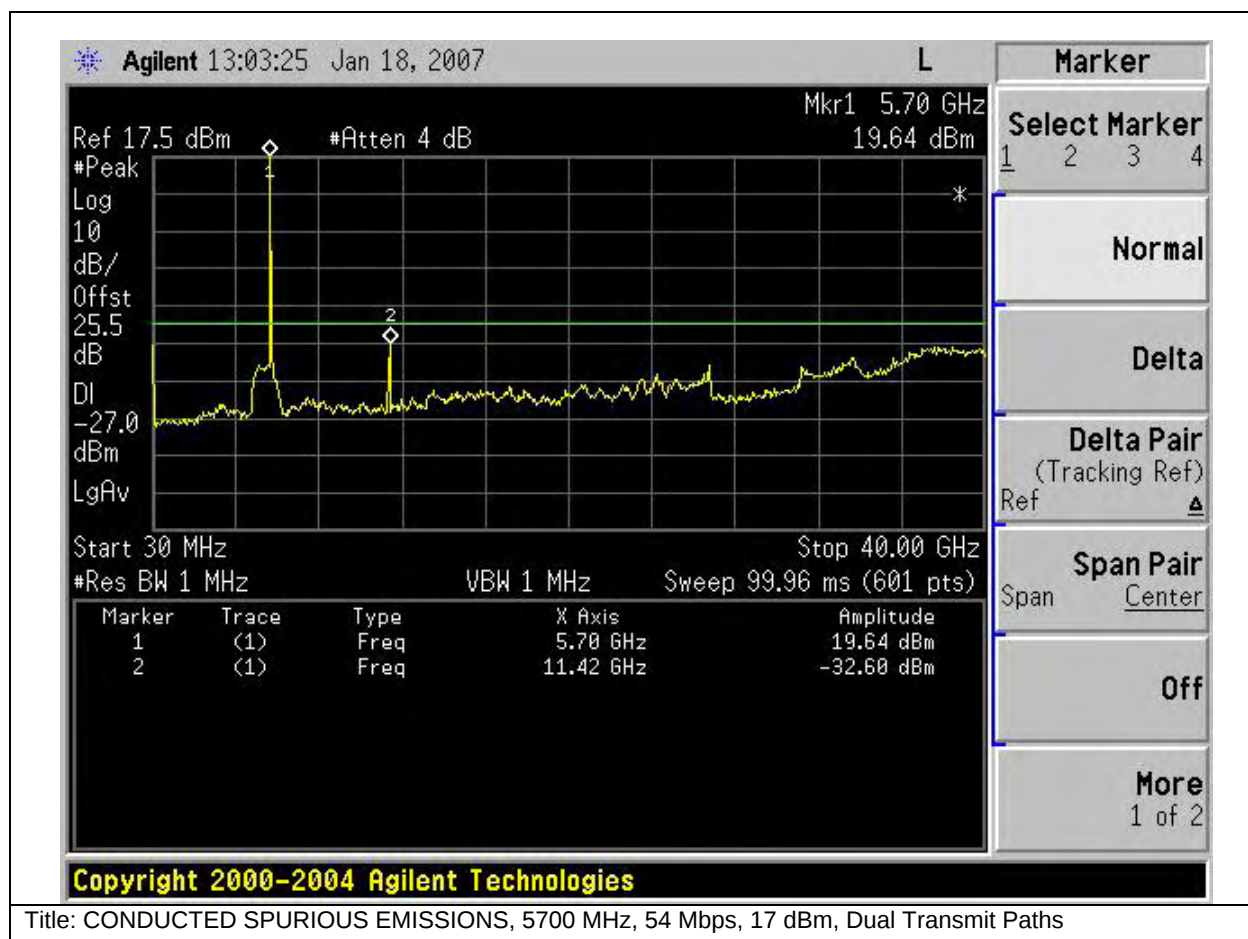
Subtest Number: 25260 - 11		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



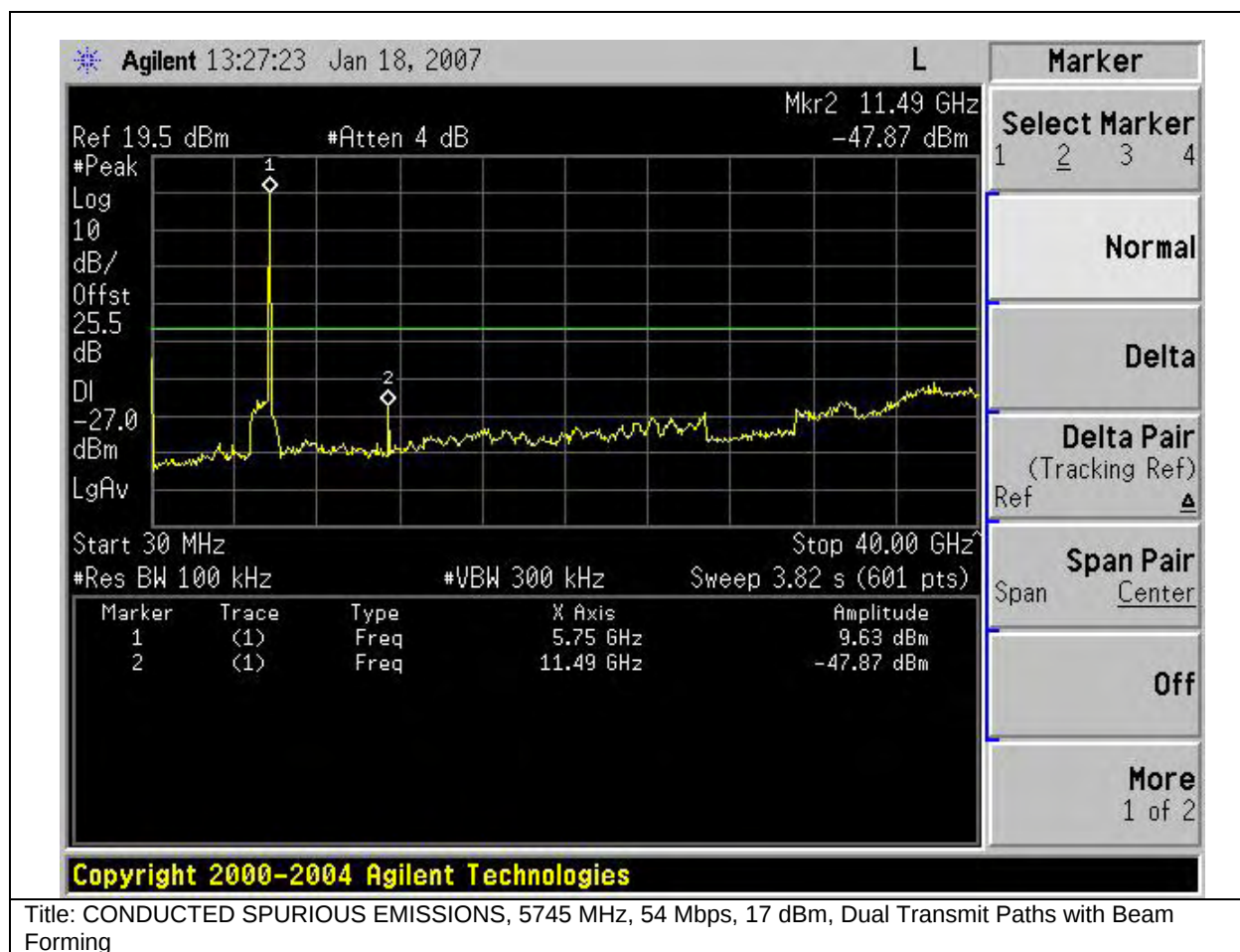
Subtest Number: 25260 - 13		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



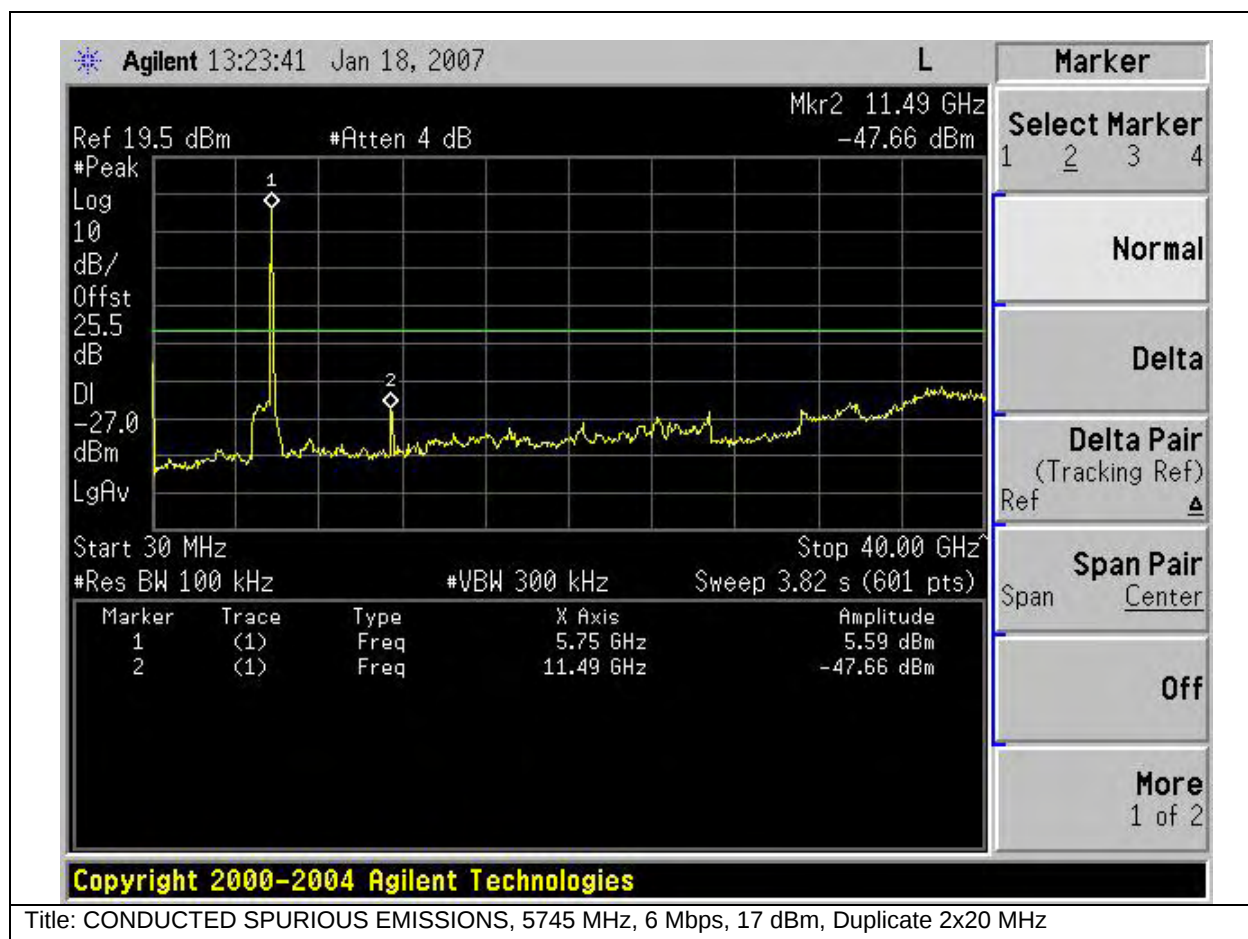
Subtest Number: 25260 - 14		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



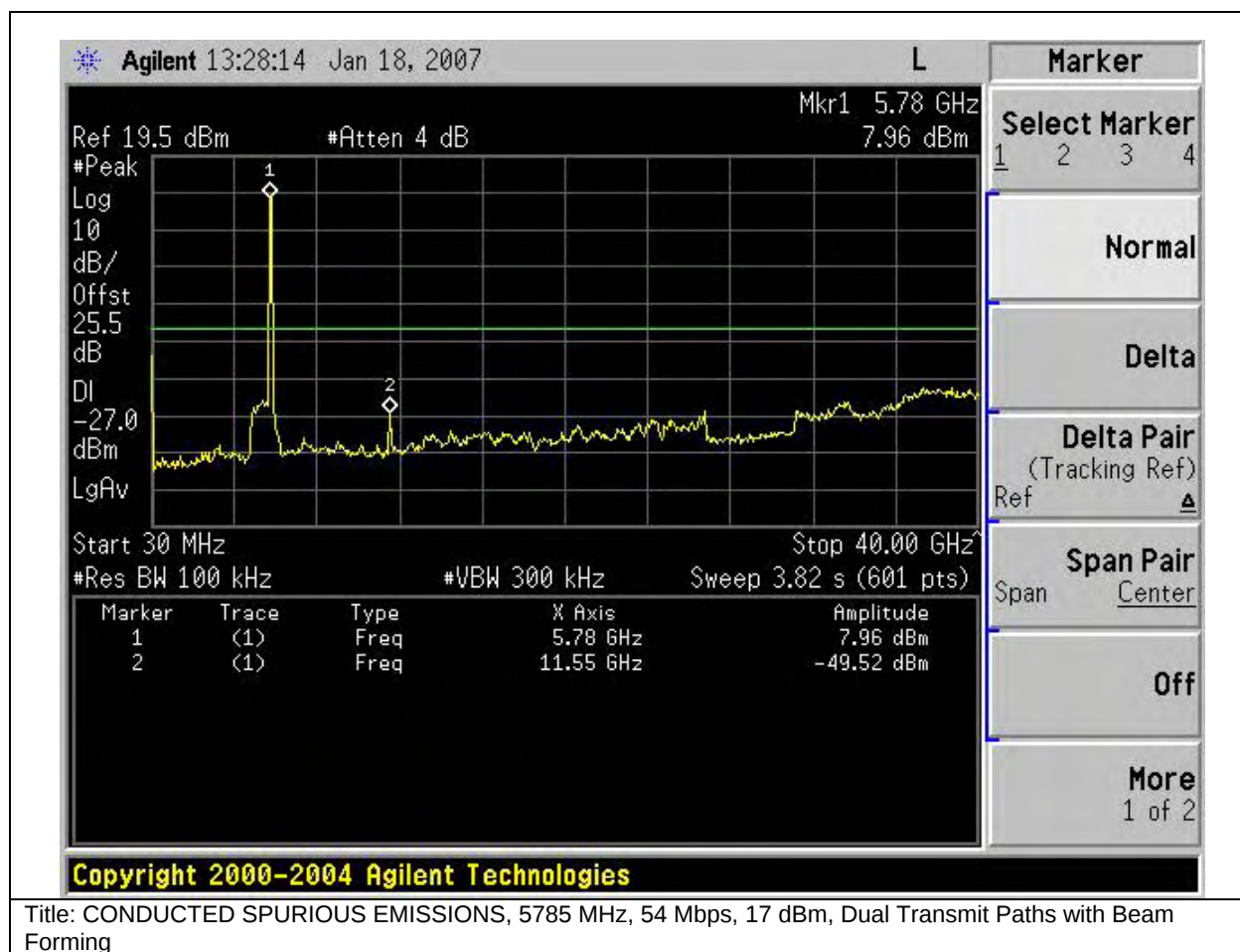
Subtest Number: 25260 - 16		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



Subtest Number: 25260 - 15		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



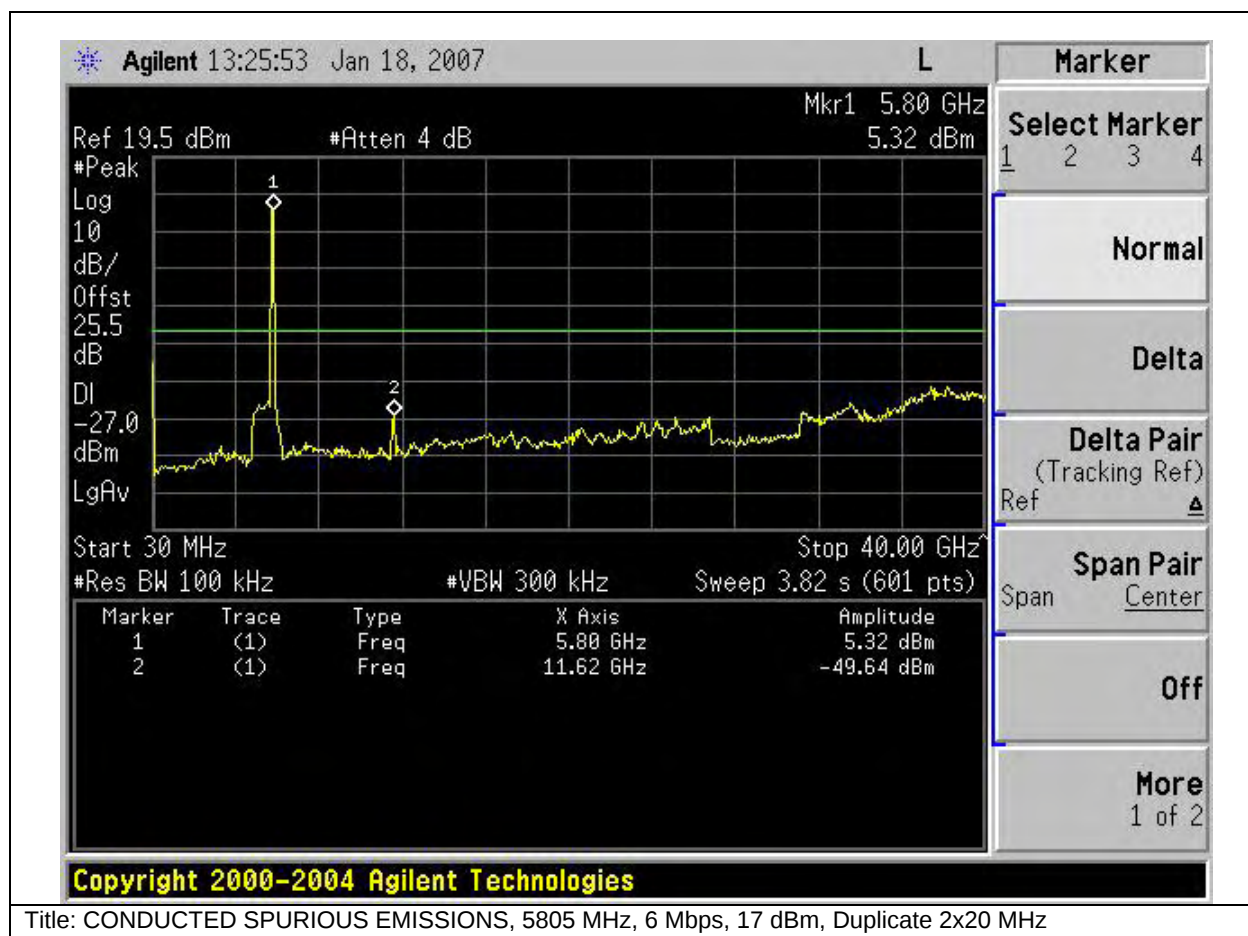
Subtest Number: 25260 - 18		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



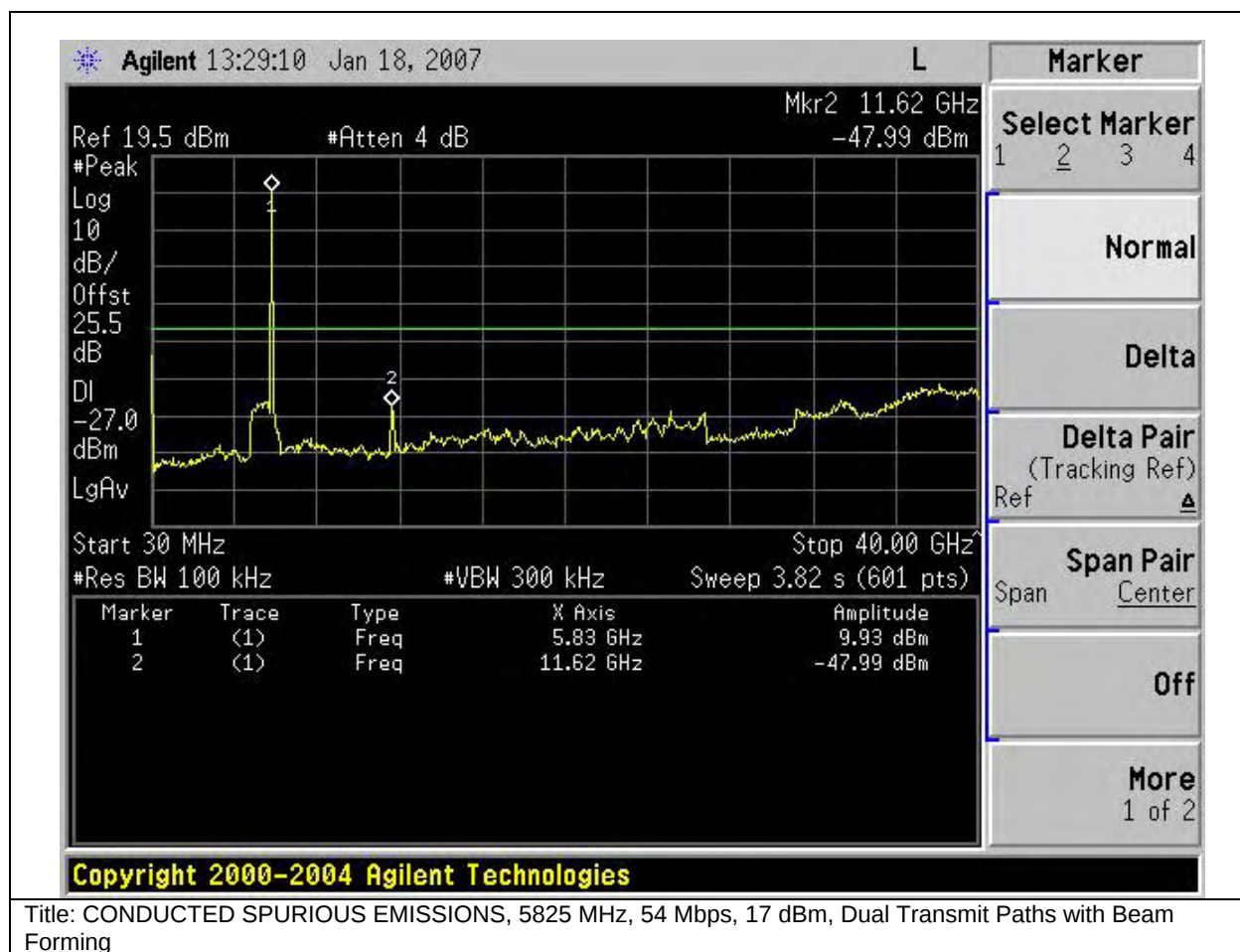
Subtest Number: 25260 - 17		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	

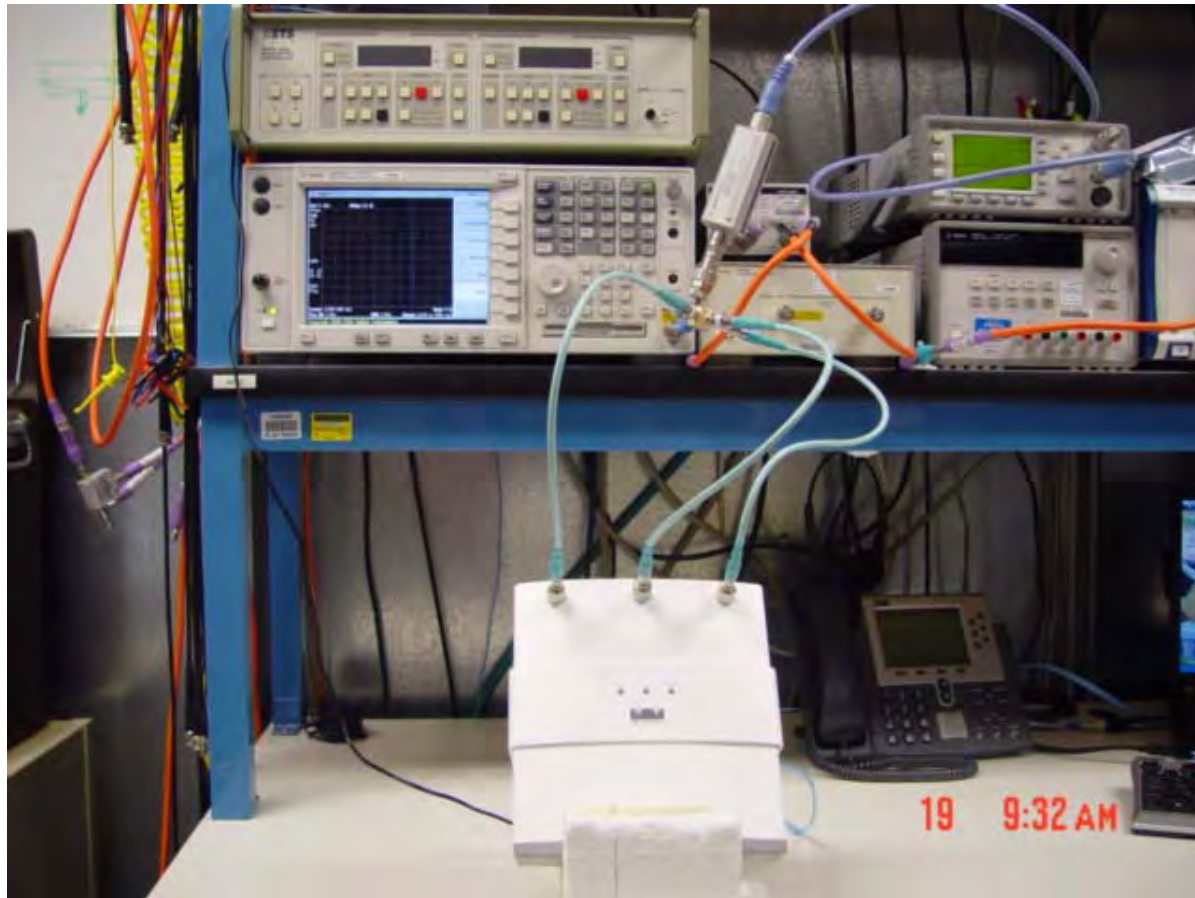


Subtest Number: 25260 - 19		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	



Subtest Number: 25260 - 20		Subtest Date: 24-Jan-2007
Engineer	James Nicholson	
Lab Information	Richfield, EMC Labs	
Subtest Results		
Line Under Test	RF Port	
Transducer	Direct	
Subtest Result	Pass	
Highest Frequency	N/A	
Lowest Frequency	N/A	
Comments on the above Test Results	No further comments	





Title: Conducted Test Setup